

C|D|T

**Polymer-OLED Technology:  
Improvements in Device  
and Materials Performance**

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CTO

**FPD International**  
2004 -DISPLAYING THE FUTURE-

October 2004

Introduction

Understanding PLEDs

Tri Layer PLEDs

Singlet:Triplet Ratio

Conclusions

**New or Modified**

Introduction

Understanding PLEDs

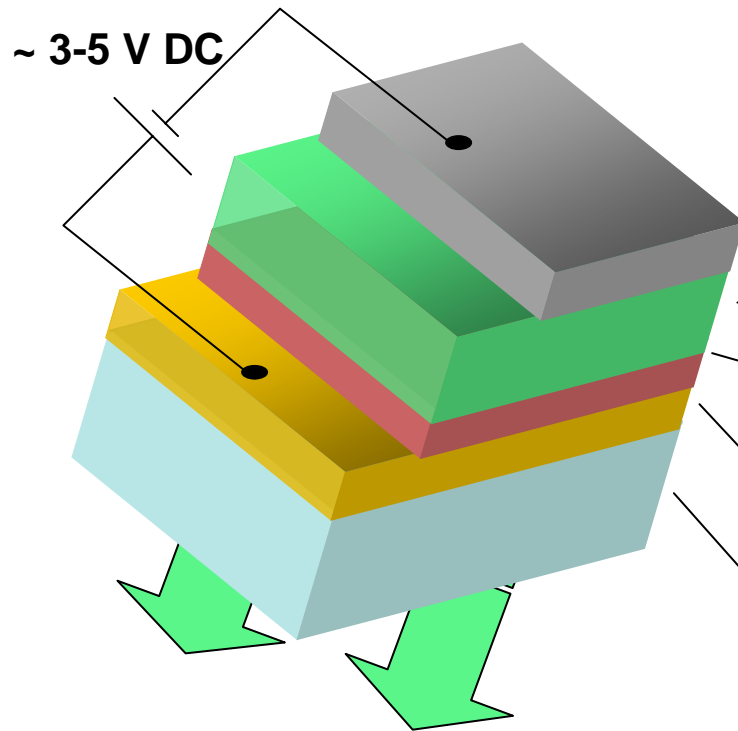
Tri Layer PLEDs

Singlet:Triplet Ratio

Conclusions

# Polymer LED Devices

- Simple device structure
- Uniform, area Emitter
- Flexible devices possible



Low workfunction metallic cathode

Thin (<100 nm) emissive layer of polymer (LEP)

Transparent hole transporting layer (PEDOT/PSS) (70 – 200 nm)

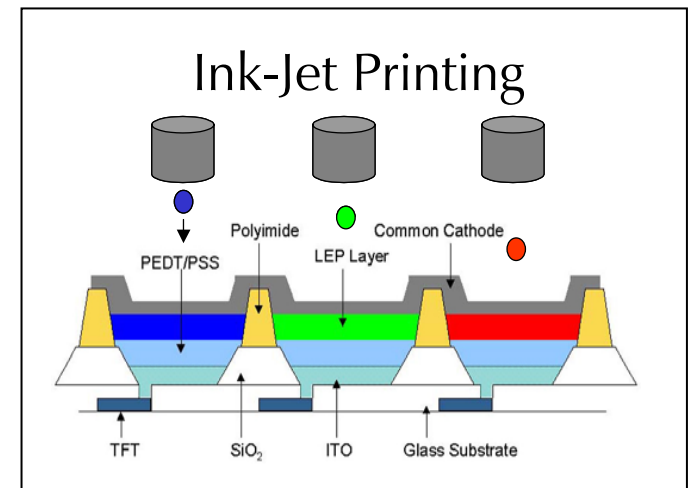
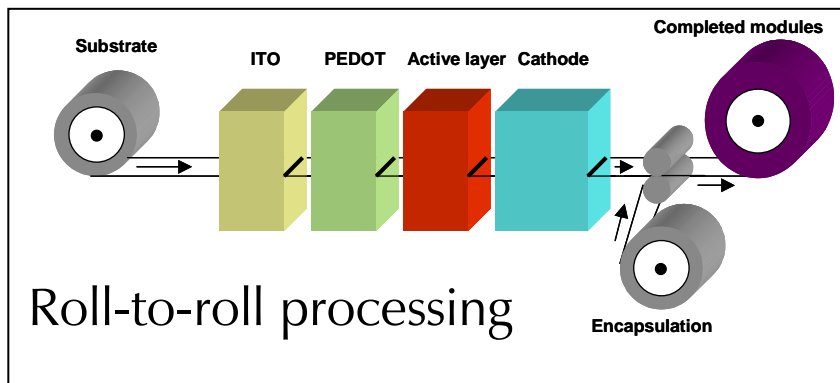
Transparent anode (e.g. ITO)

Glass/Plastic substrate

# PLED Materials and Fabrication

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- Polymer semiconductors are solution processable materials
- Colour tuning through molecular design
- Wide range of deposition processes feasible
- Low manufacturing and plant cost
- Efficient materials utilisation
- Compatible with flexible substrates



Introduction

Understanding PLEDs

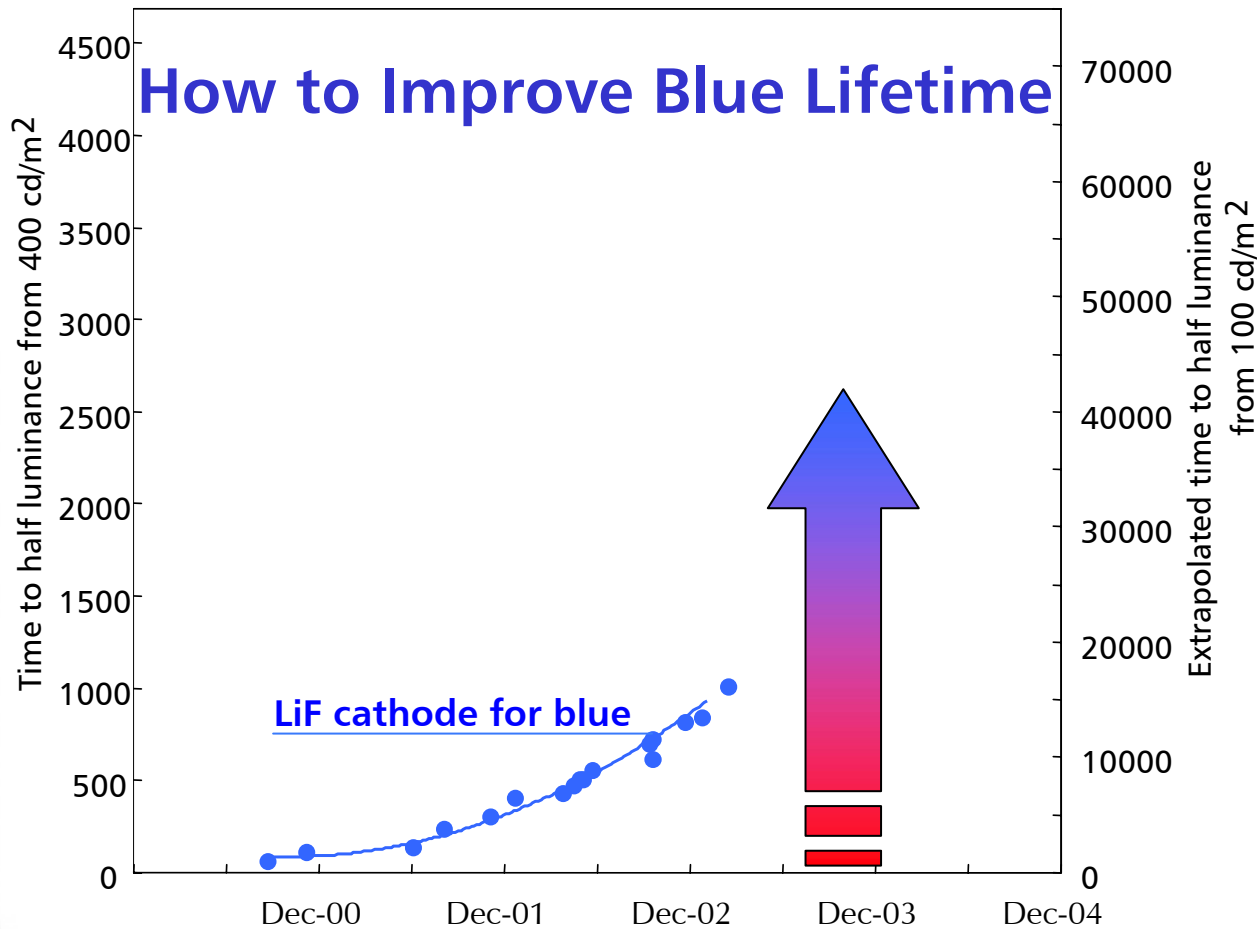
Tri Layer PLEDs

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# Blue Lifetime Progress

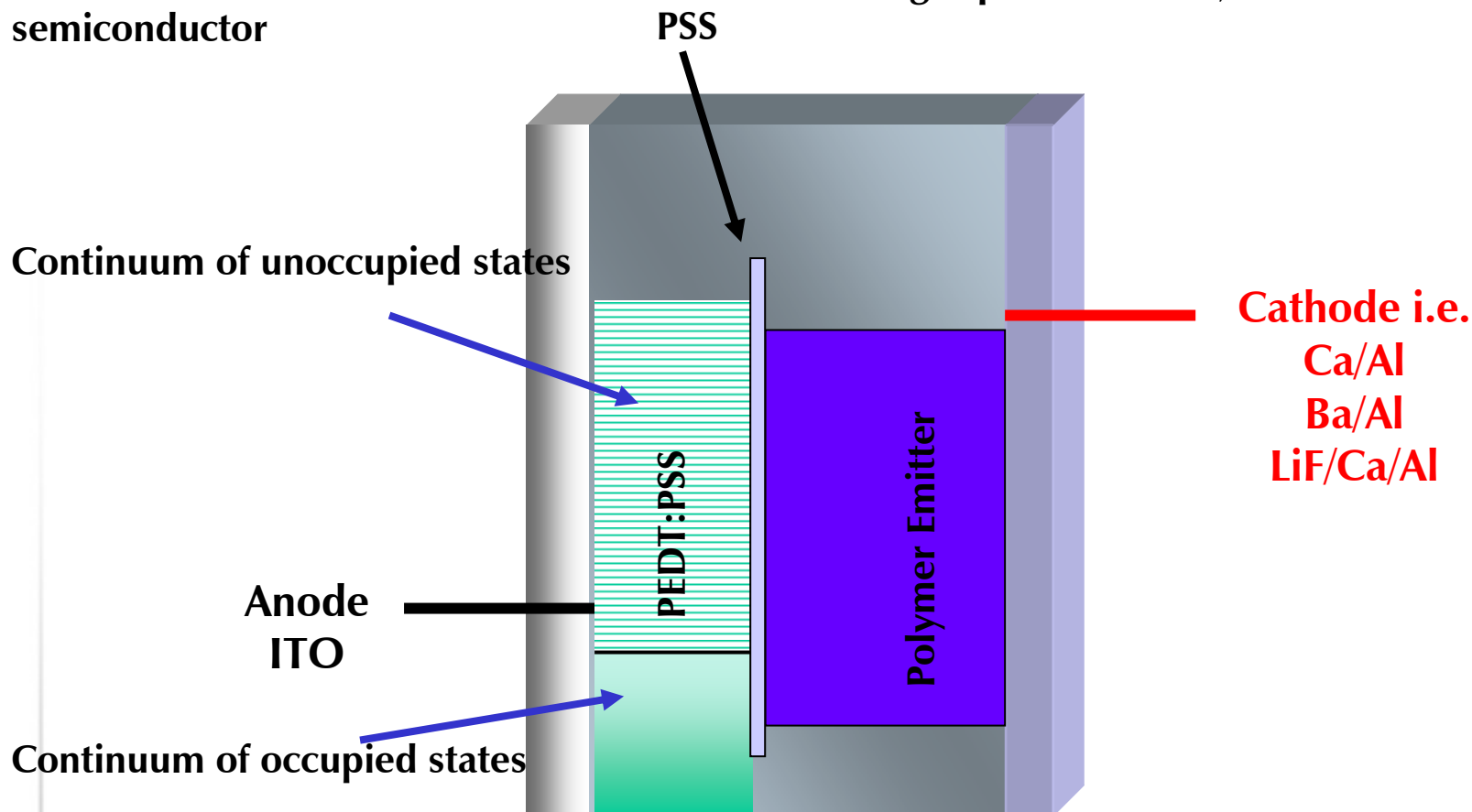
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# Basic Device Structure

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Note: PEDT:PSS is disordered metal with  $\sim 0.3$  charges per PEDT unit, it is not a semiconductor

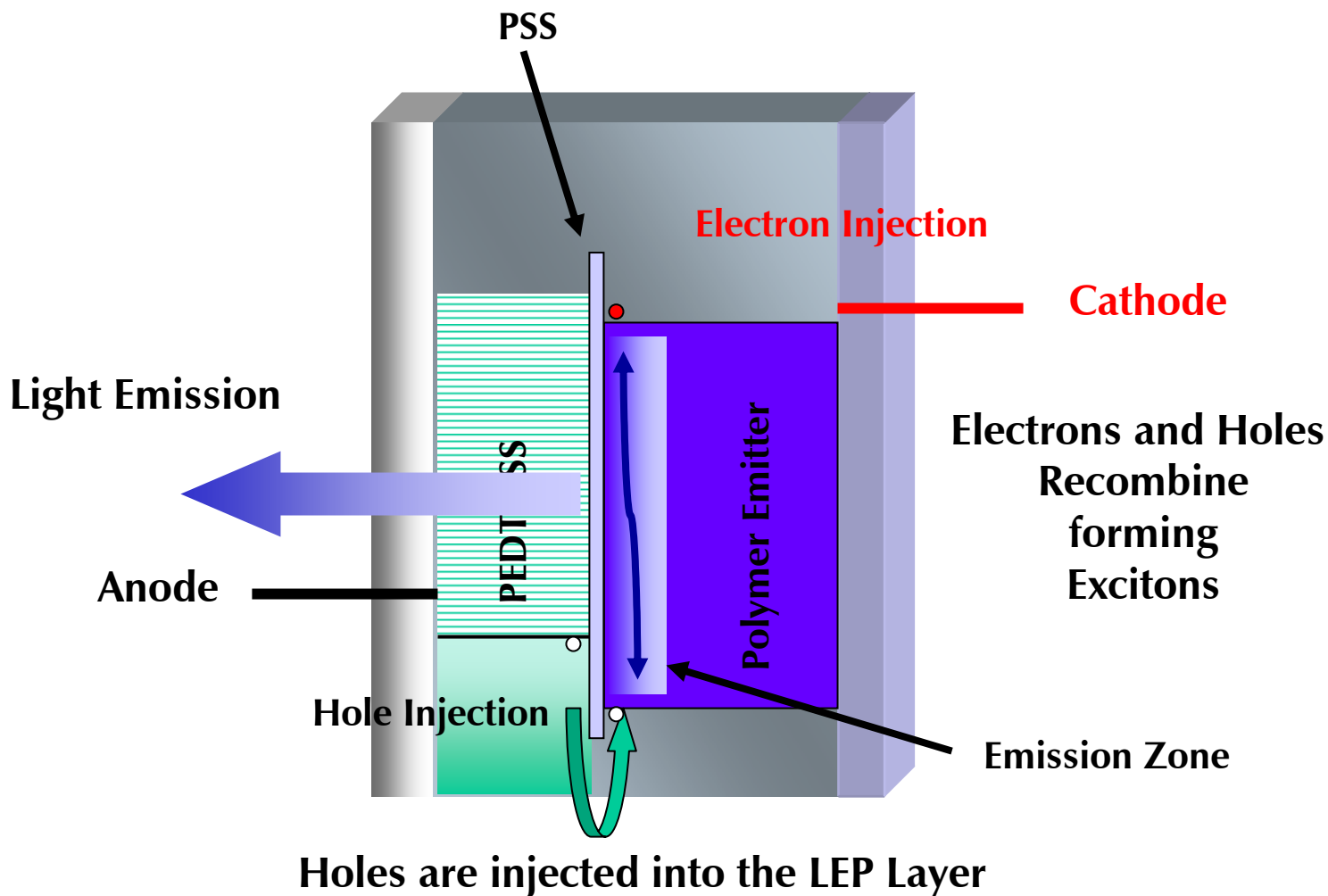


Neutron Scattering on deuterated PEDT:PSS shows that the surface is PSS rich,  
Circa 5 - 10 nm thick



# Ideal Device Operation

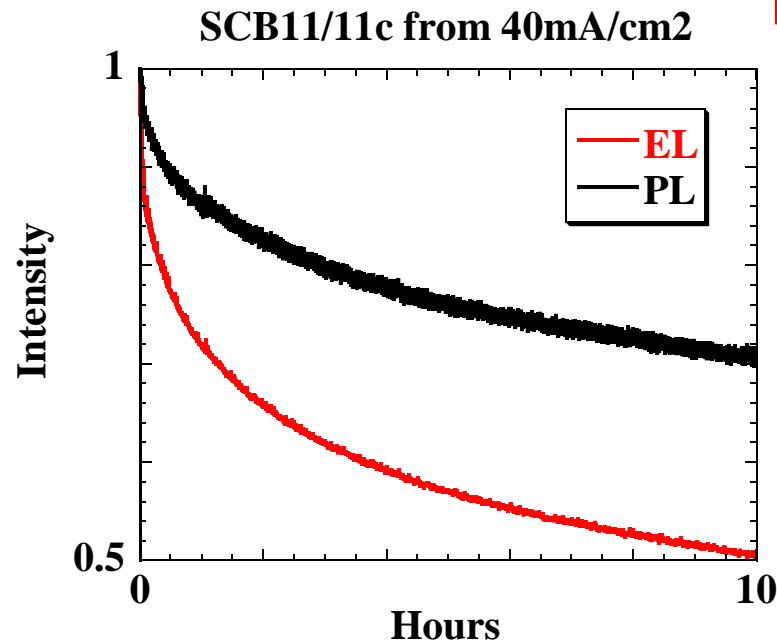
C|D|T



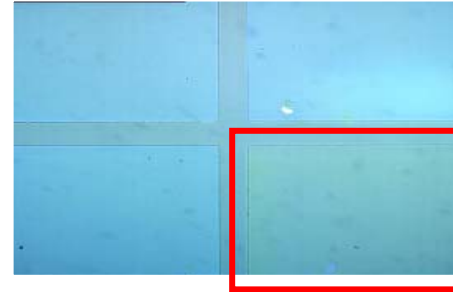
- CDT has developed techniques for reverse engineering PLED devices – layer by layer
  - The cathode is removed by an acid wash
    - Exposing the LEP surface
  - The soluble LEP is removed by solvent wash
    - Exposing PEDT:PSS surface for un-driven devices
    - Exposing insoluble LEP for driven devices
  - Insoluble and soluble LEP can be lifted off by dissolving PEDT
    - Thus LEP can be examined separately
  - Reverse Engineering Helps CDT Understand Degradation

New or Modified

# PL decay and insoluble layer



## Photoluminescent Images



After acid  
rinse LEP  
Exposed



After solvent  
rinse PEDT  
exposed for  
un-driven  
devices

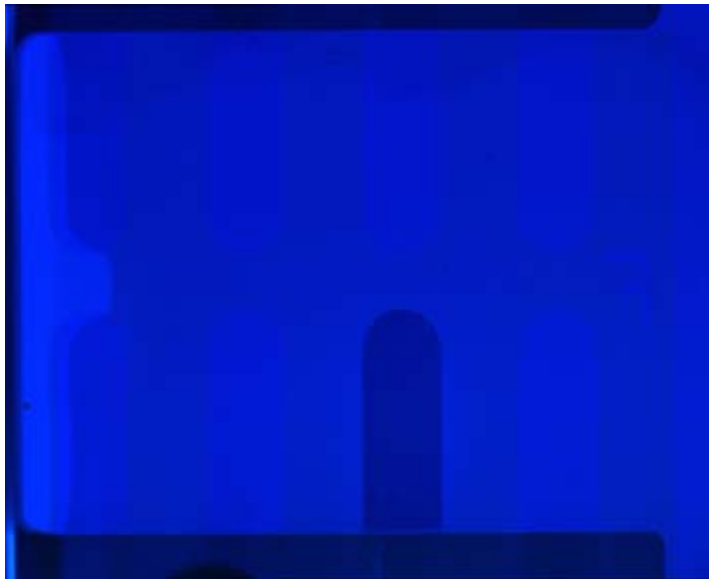
- PL intensity is reduced with driving
- Insoluble layer remains after cathode removal and solvent rinse

**Driven Pixel**

## Photoluminescent Image of Driven and un-Driven Devices

**SCB bipolar**

Pixel 2 - 960hrs at 4mA/cm<sup>2</sup>



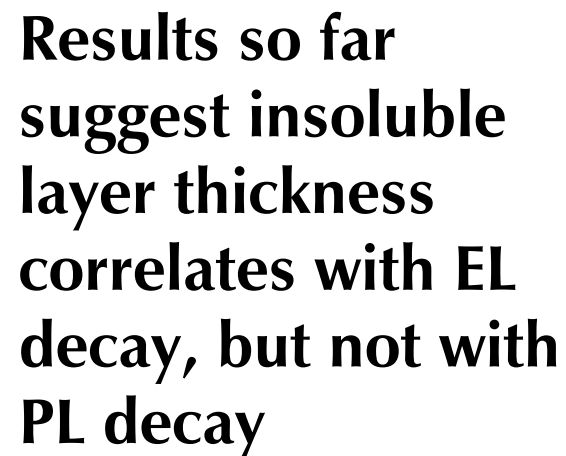
**SCB hole only device**

Pixel 2 - 960hrs at 4mA/cm<sup>2</sup> Pixel 3 - 290hrs at 32mA/cm<sup>2</sup>



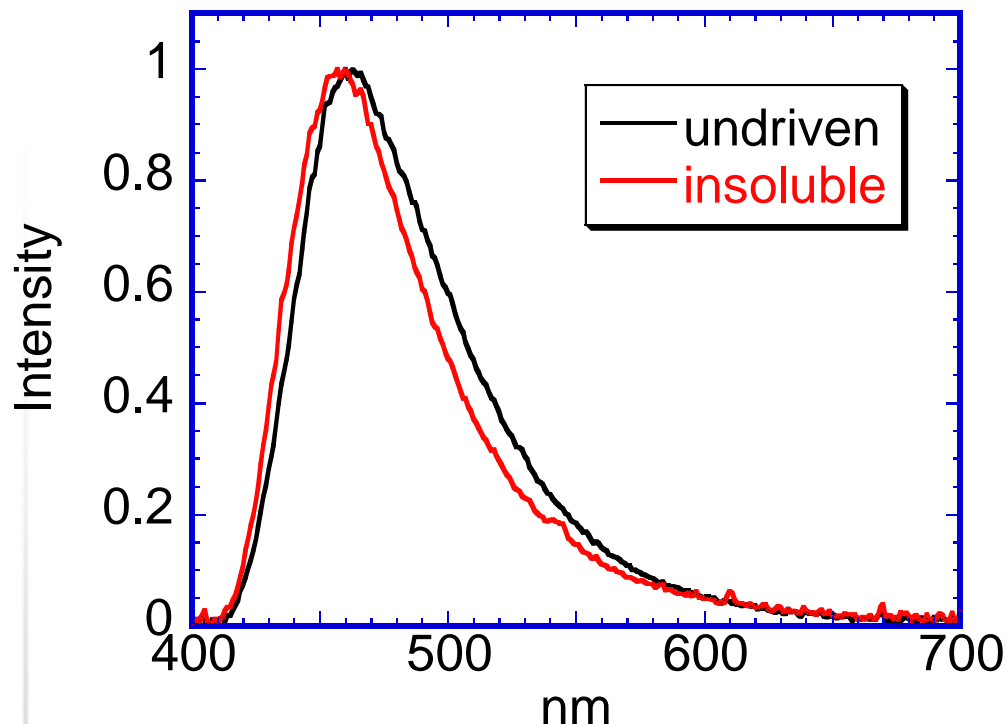
- PL does not seem to decay in hole only devices despite 5 times charge fluence
- Results suggest no PL decay in electron only devices either

## C | D | T

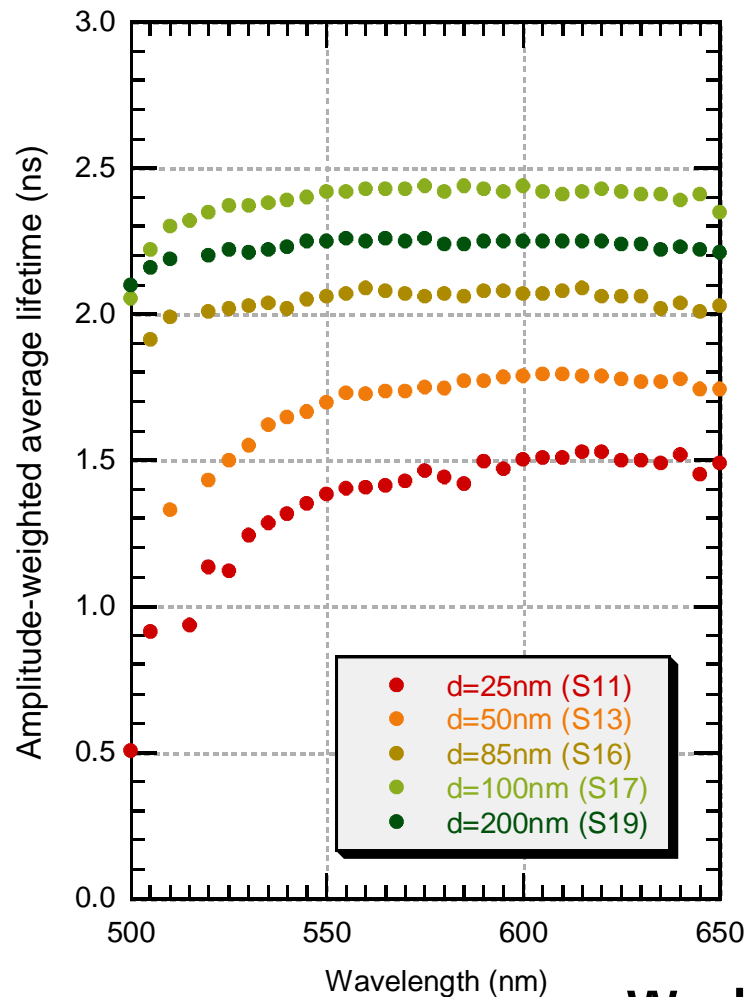


# Insoluble layer properties

PL spectrum of Insoluble SCB11



- Lower PL yield than pristine films
- Spectral shifts – blue shift often observed, but looks like could be an artefact
- Solubility – insoluble in THF, MeOH, acetone, xylene – heated for 30mins



**Test Structure:**  
**PEDT:PSS/Green LEP**  
Where LEP Thickness is 25 – 200 nm

**Measure Exciton Lifetime**

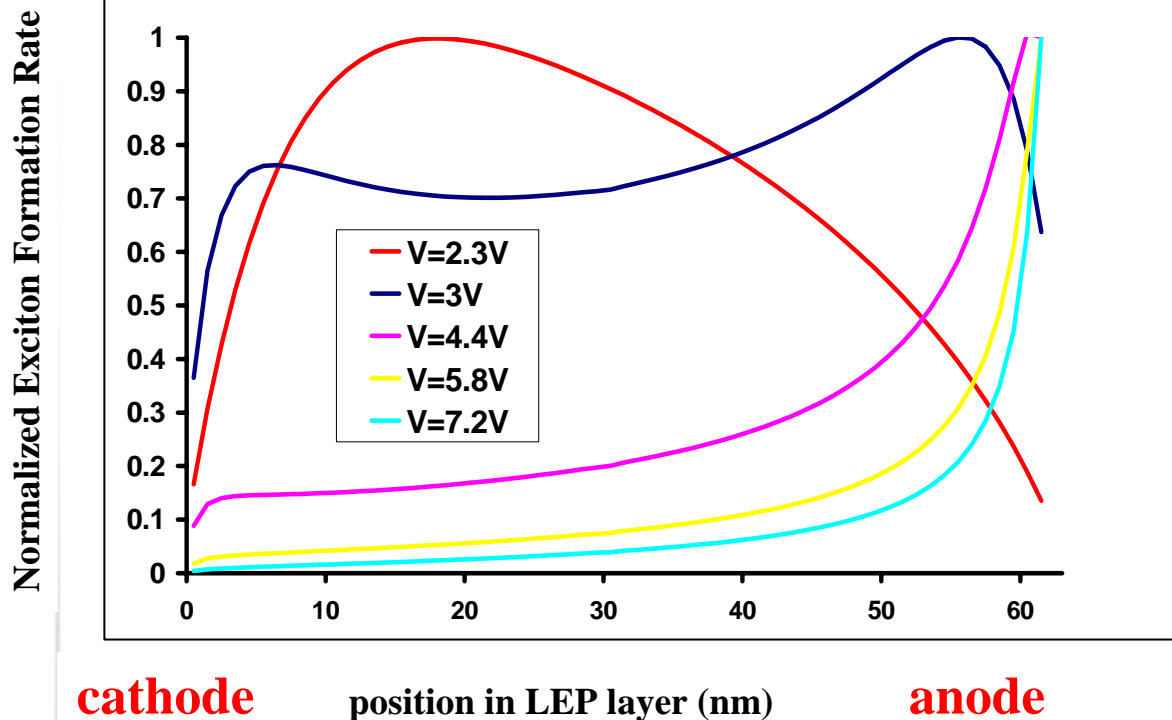
**Observation:**  
**Shorter Lifetime for thin LEP**  
**I.E. PEDT Quenches Excitons**

**Work done at the Cavendish Laboratory**

# Electrical modelling: Blue Device

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- Integrated with experiment – fit device I-V characteristics
- Determine injection mechanisms, charge balance & exciton formation zone profile
- As a function of device geometry and layer materials



At low voltage  $m_h > m_e$   
RZ towards cathode

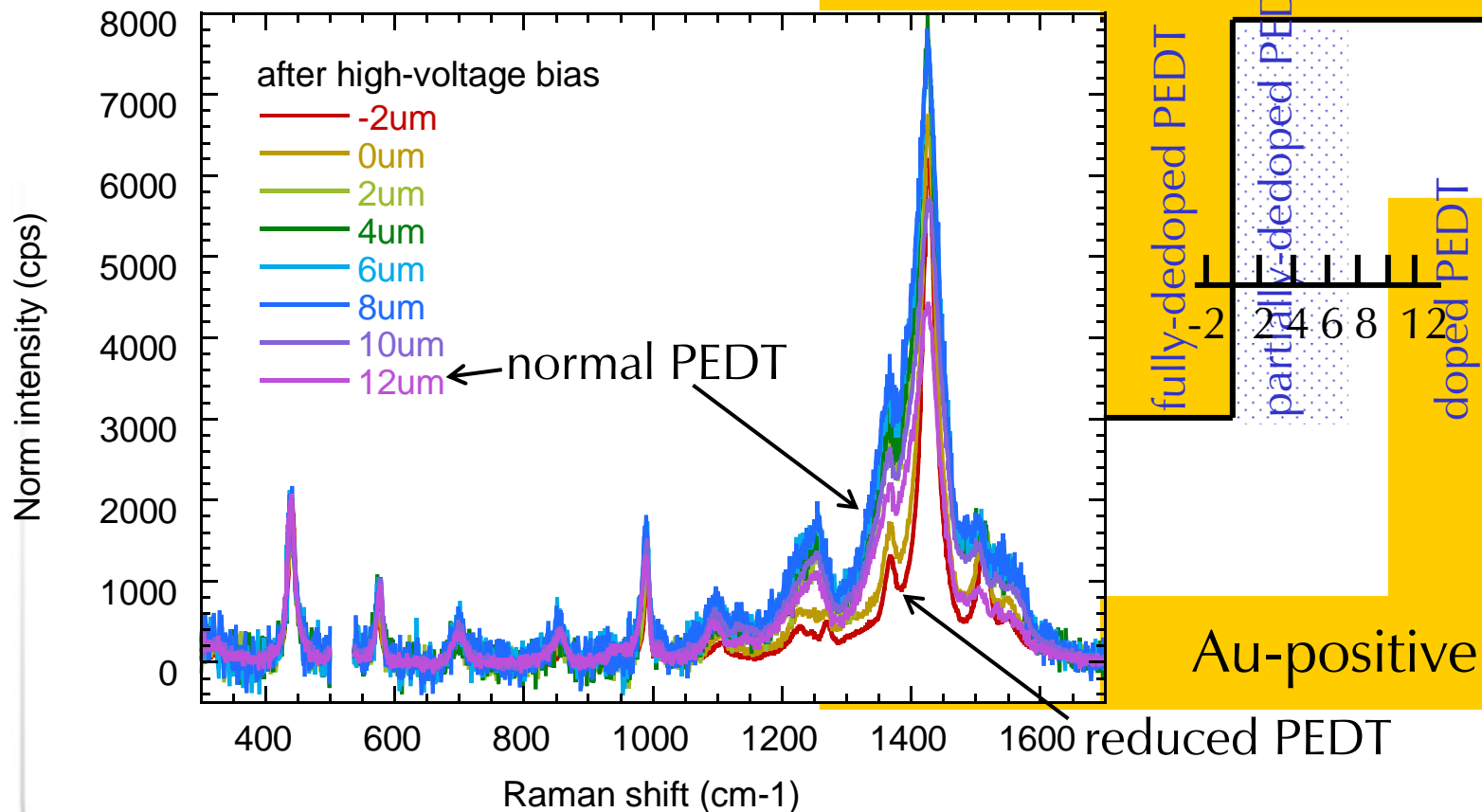
$V > 2.8$ ,  $m_e > m_h$   
RZ towards anode

@ Operating Point  
exciton formation zone  
adjacent to PEDT



# Possible Evidence for Electron Damage C|D|T

MicroRaman analysis  
after 50kV/micron drive bias



Work done at the Cavendish Laboratory

## Summary

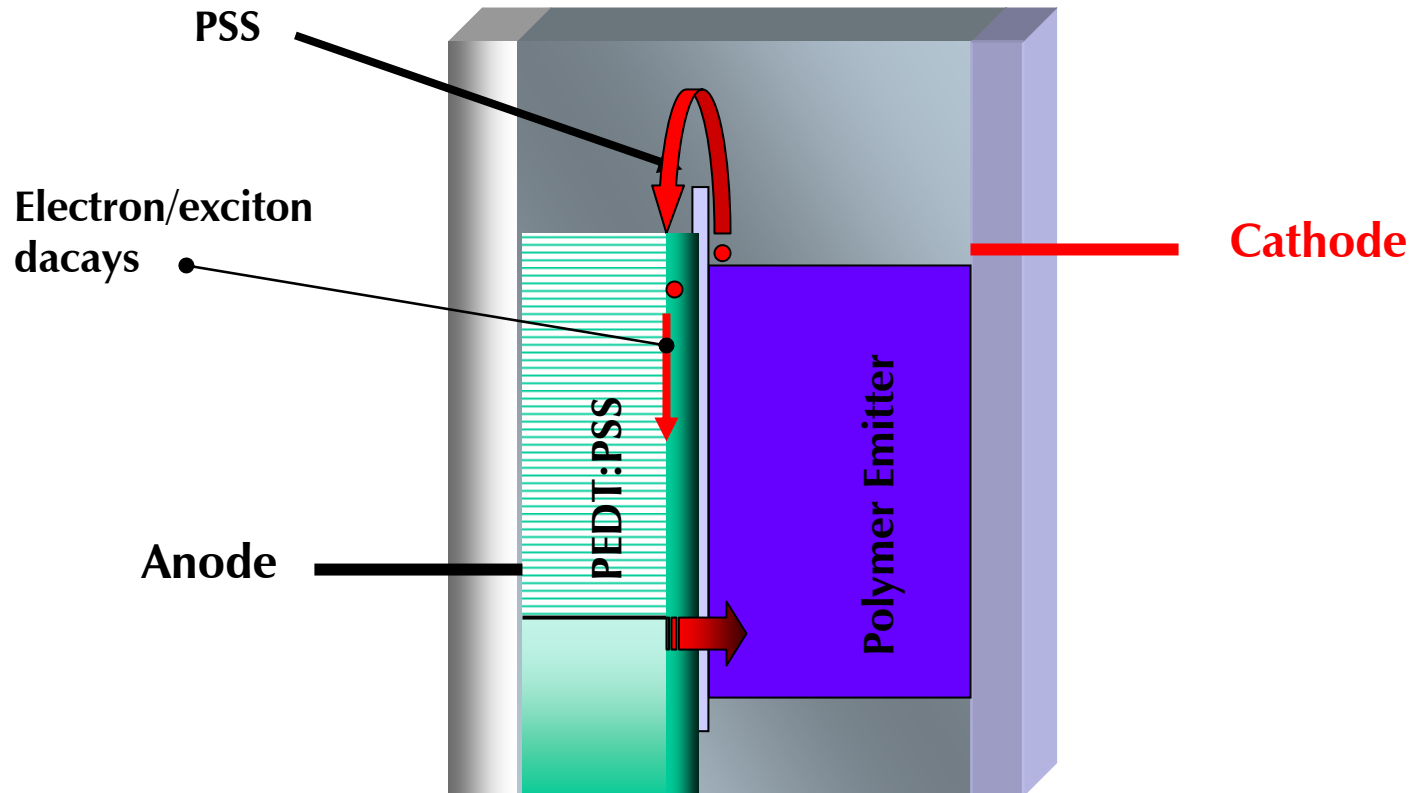
- Insoluble LEP layer forms with driving of device
  - Thickness correlates with EL decay very well
  - Growth from PEDT:LEP interface
- Holes show no evidence of degradation
  - LEP or PEDT
- Electrons show no evidence of degradation in LEP
- Insignificant PL spectrum change
- Exciton Formation near PEDT:LEP Interface
  - Therefore Electron Accumulation
- Significant Exciton Quenching at PEDT:LEP Interface
- Evidence for change in PEDT with Electron Injection

New or Modified

# Proposed Device Decay Mechanism

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Some electrons/excitons injected into PEDT:PSS



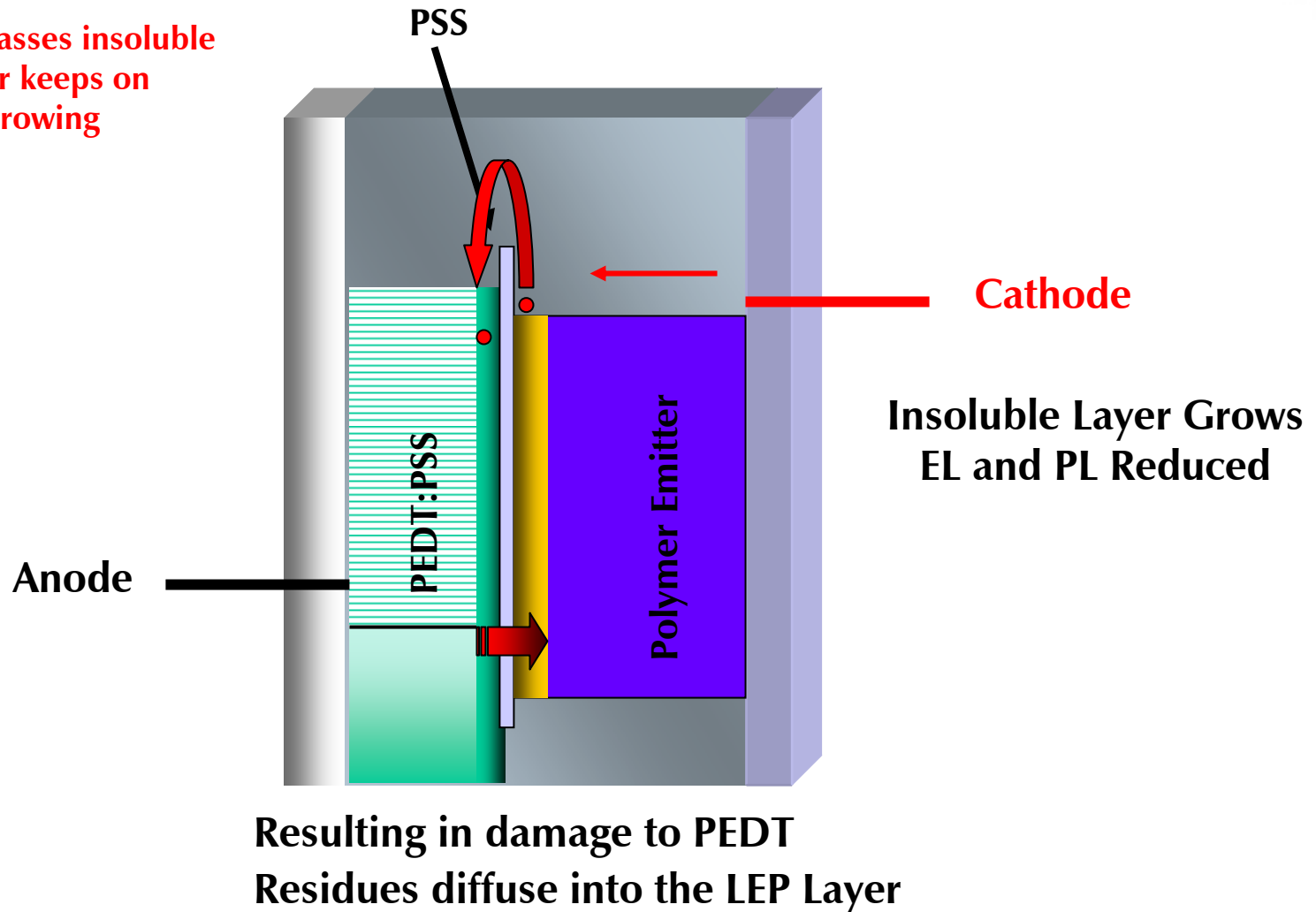
Resulting in damage to PEDT:PSS  
Residues diffuse into the LEP Layer

# Device Decay Mechanism

C|D|T

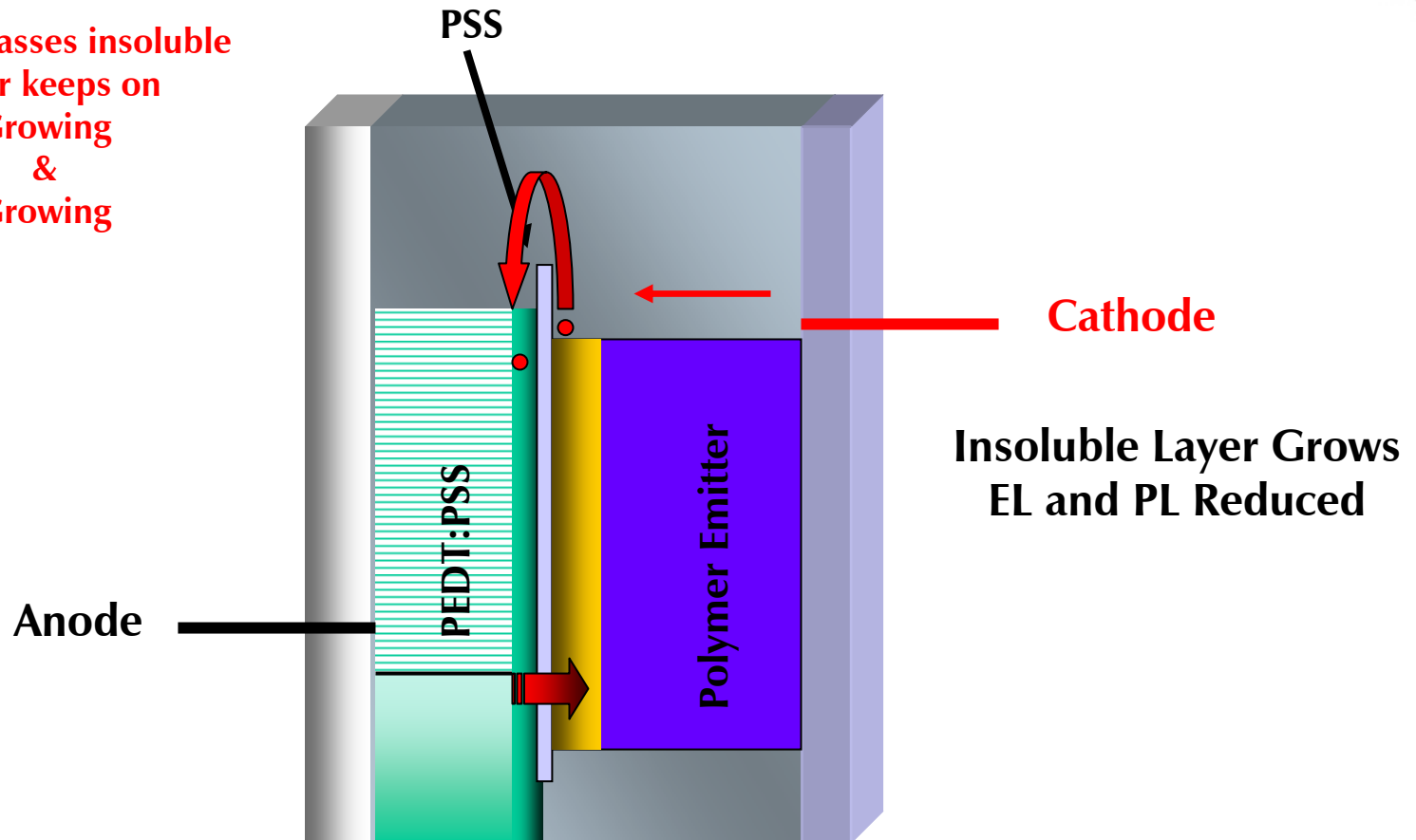
Some electrons/excitons injected into PEDT:PSS

As time passes insoluble  
Layer keeps on  
growing



C | D | T

**As time passes insoluble  
Layer keeps on  
Growing  
&  
Growing**



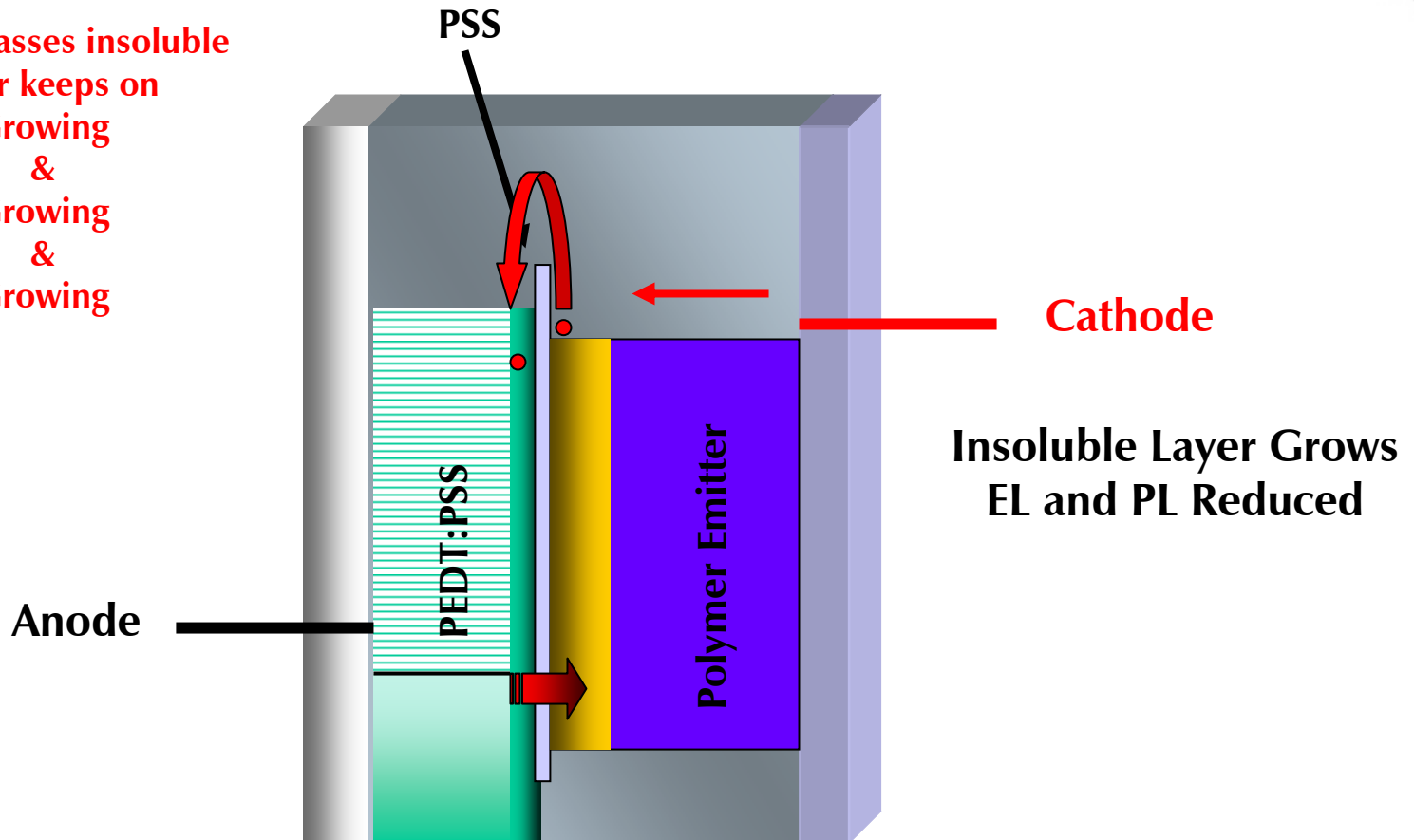
## Resulting in damage to PEDT Residues diffuse into the LEP Layer

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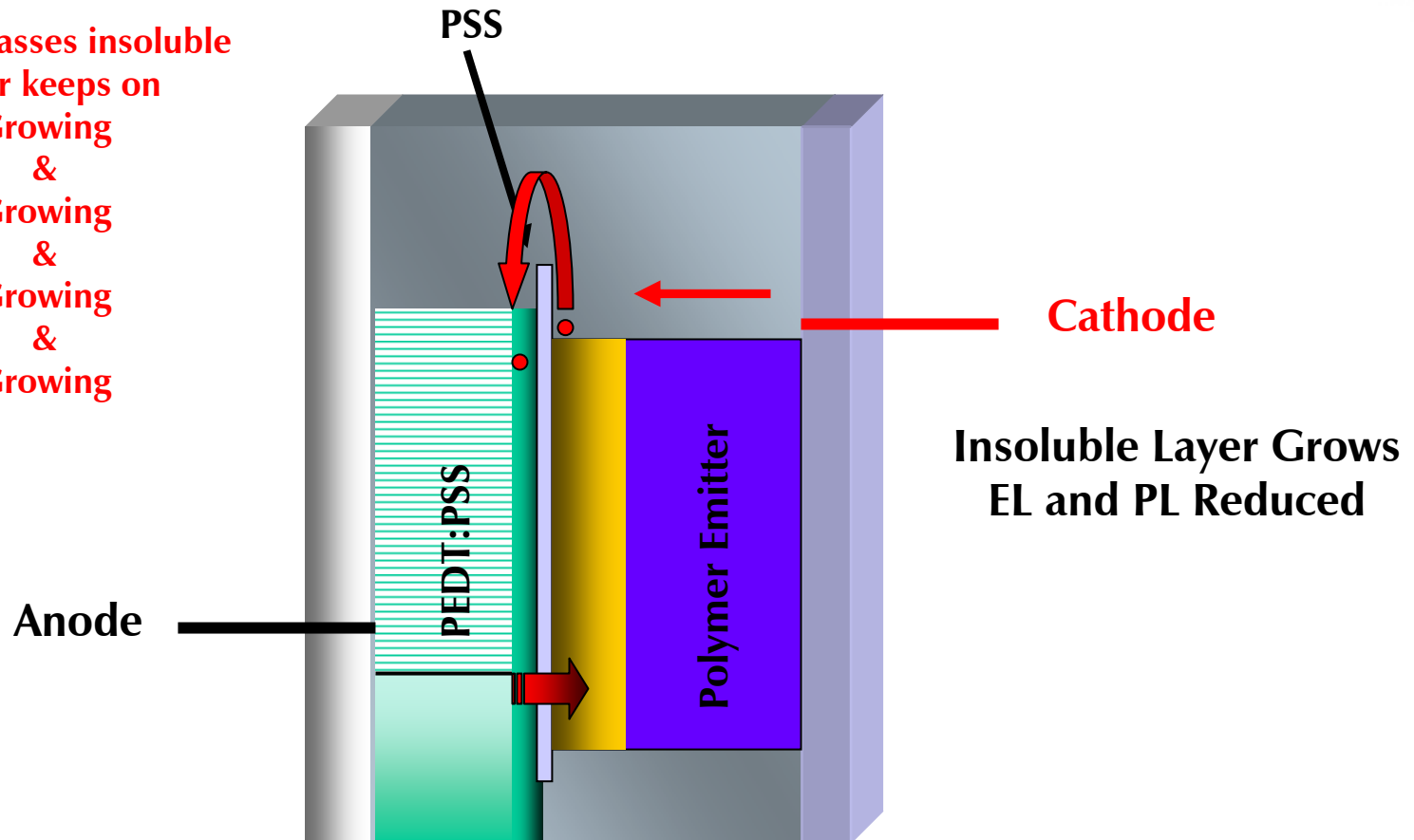
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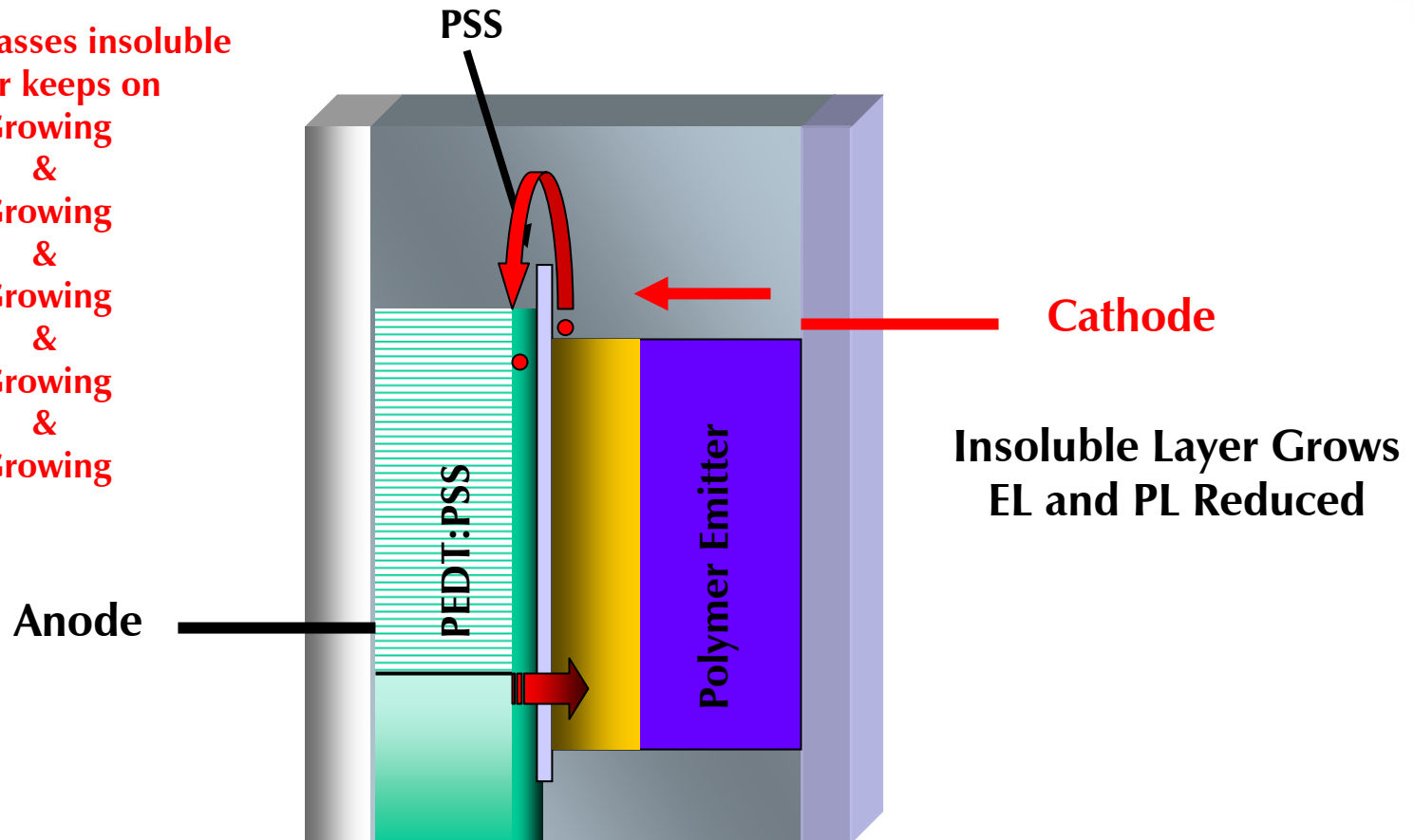
As time passes insoluble  
Layer keeps on  
Growing  
&  
Growing  
&  
Growing  
&  
Growing



Resulting in damage to PEDT  
Residues diffuse into the LEP Layer

C | D | T

As time passes insoluble  
Layer keeps on  
Growing  
&  
Growing  
&  
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&  
Growing

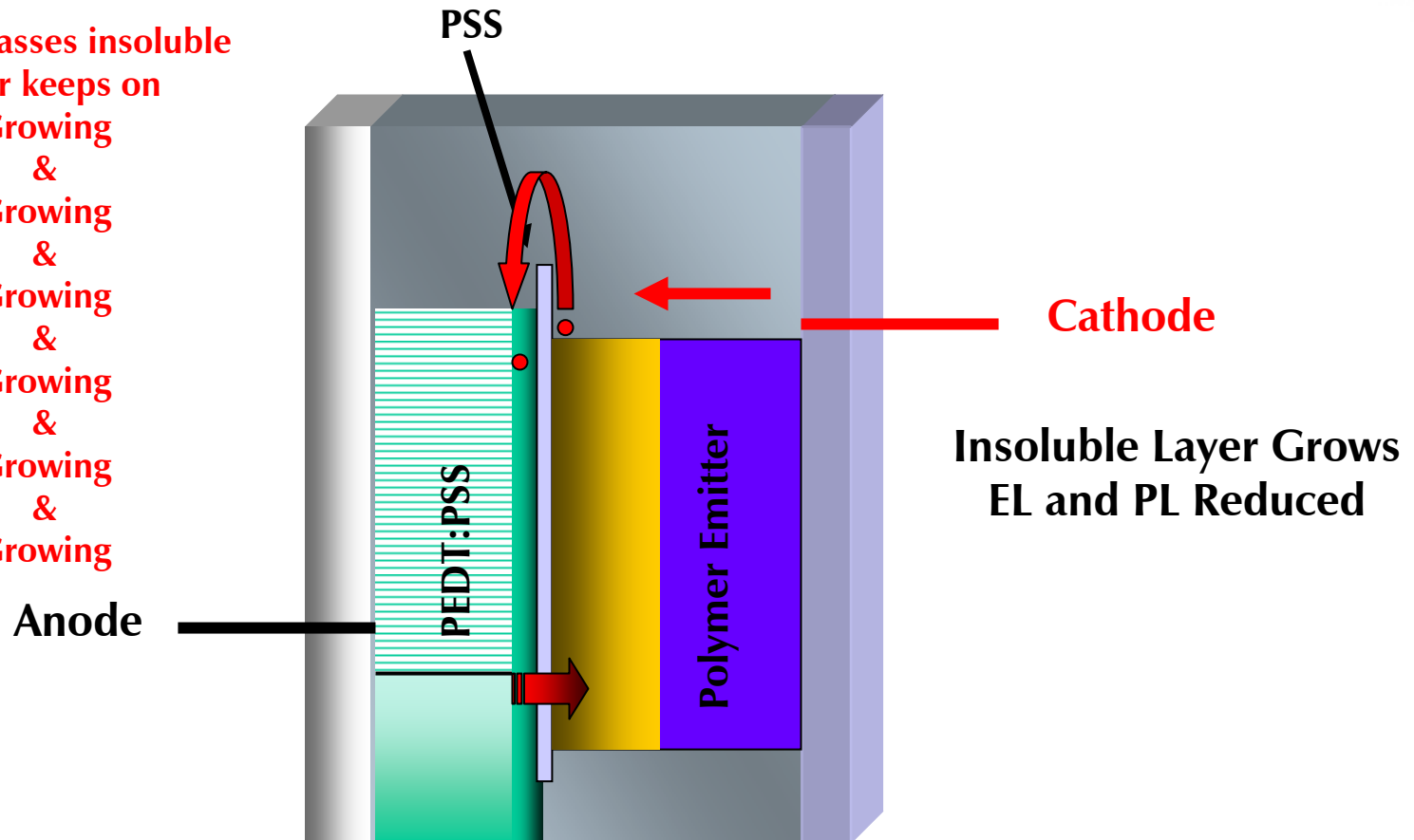


## Resulting in damage to PEDT Residues diffuse into the LEP Layer



C | D | T

**As time passes insoluble  
Layer keeps on  
Growing  
&  
Growing  
&  
Growing  
&  
Growing  
&  
Growing  
&  
Growing**



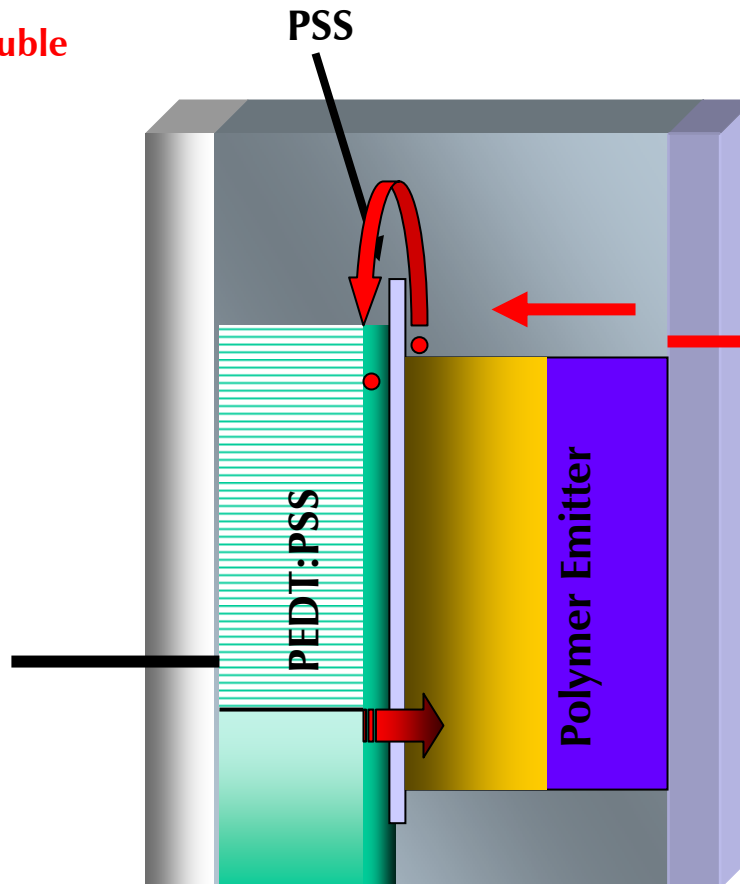
## Resulting in damage to PEDT Residues diffuse into the LEP Layer

C | D | T

**As time passes insoluble  
Layer keeps on**

# Growing

## GROWING



## Insoluble Layer Grows EL and PL Reduced

## Resulting in damage to PEDT Residues diffuse into the LEP Layer

Introduction

Understanding PLEDs

Tri Layer PLEDs

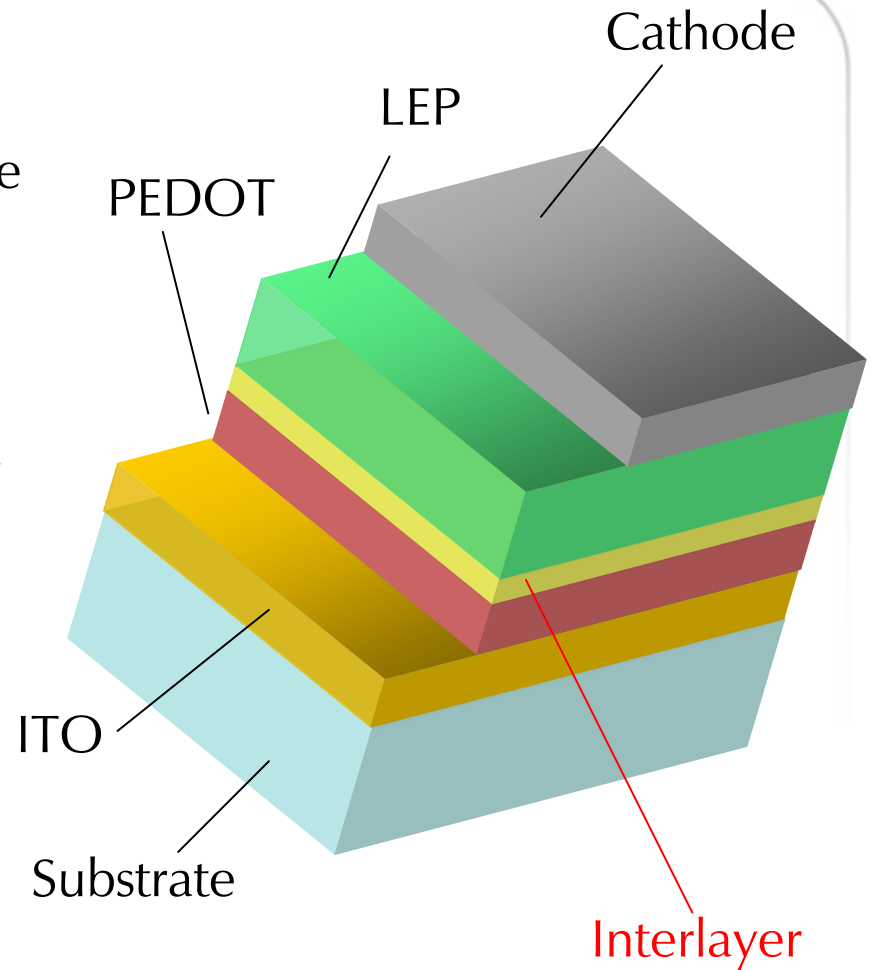
Singlet:Triplet Ratio

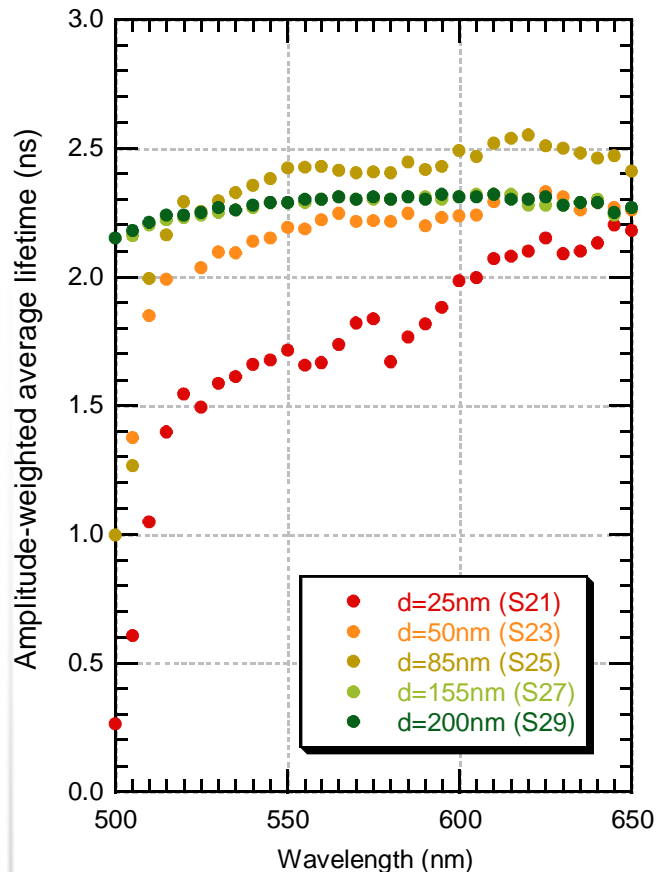
Conclusions

# PLED Progress-Blue Lifetime

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- Additional buffer layer inserted between PEDOT:PSS and emissive layer
  - Inhibit e- injection into PEDOT:PSS
  - Reduce exciton quenching at anode
- Interlayer is a polymer semiconductor deposited by solution processing
  - Compatible with ink jet printing





**Test Structure:**  
**PEDT:PSS/Interlayer/Green LEP**  
**Where LEP Thickness is 25 – 200 nm**

**Observation:**  
**Reduced Quenching at PEDT**

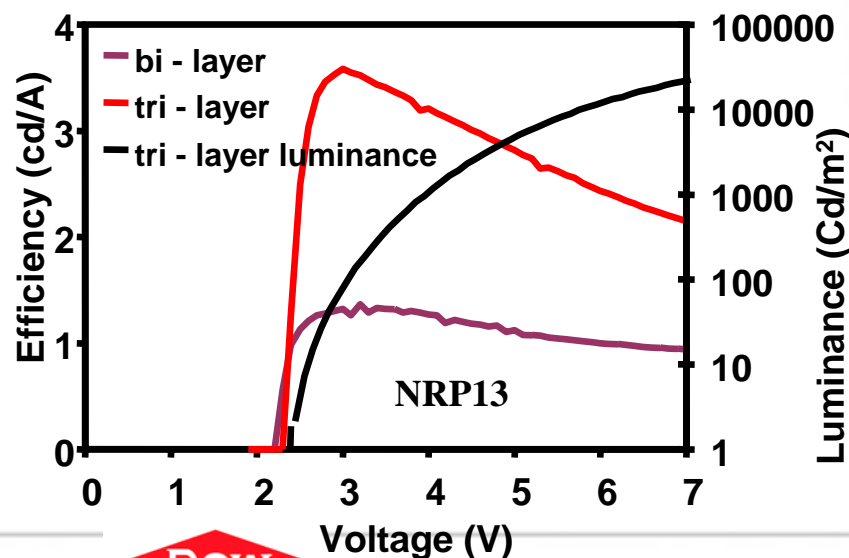
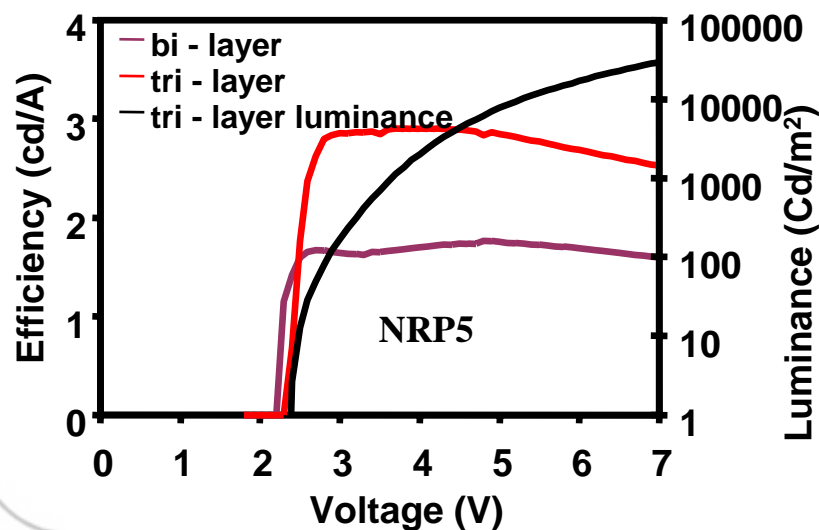
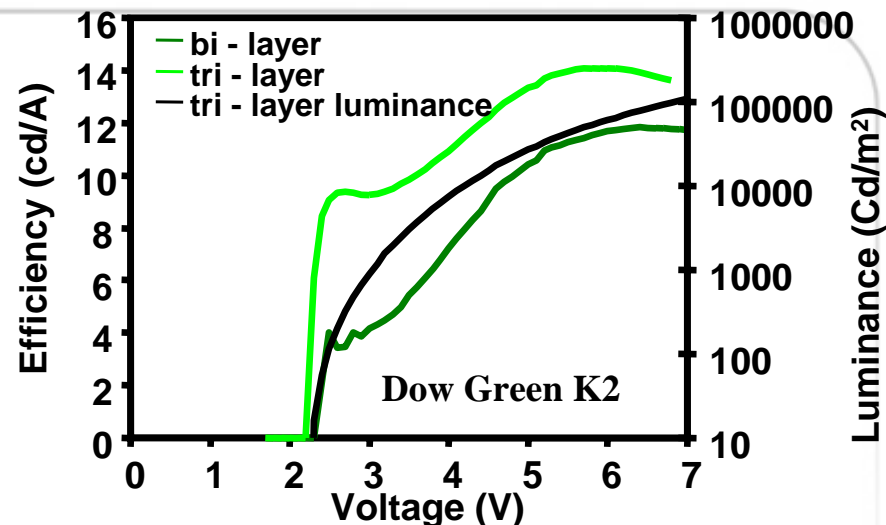
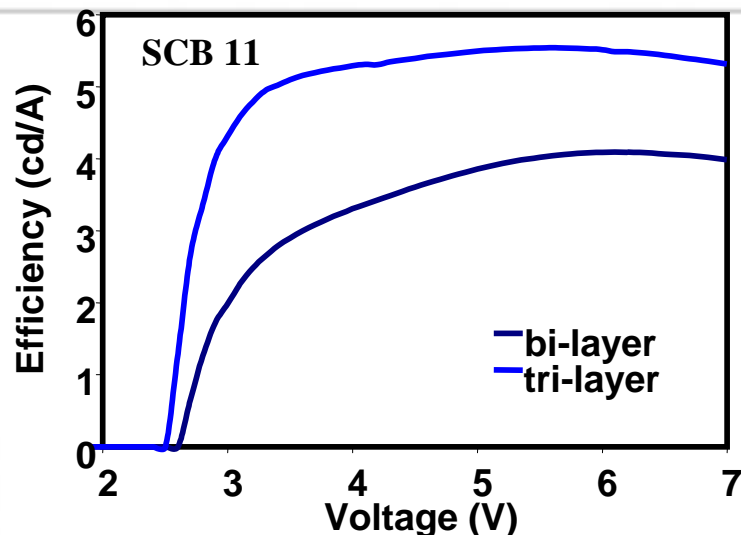
**Work done at the Cavendish Laboratory**



# Dow LUMATION™ LEP Materials

## Efficiency Increases

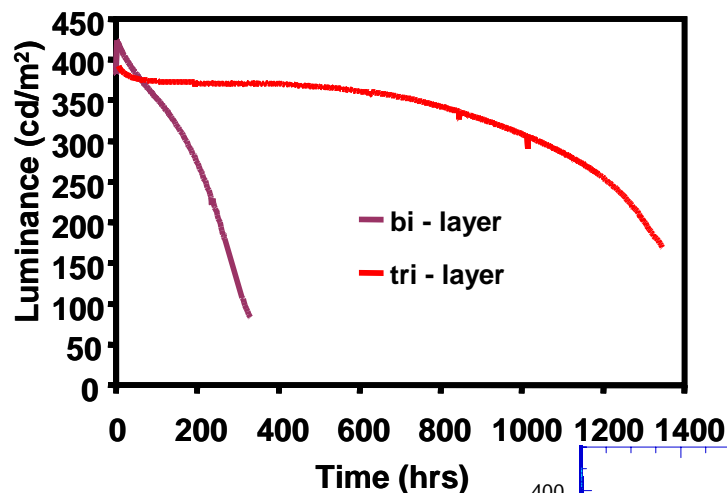
C|D|T



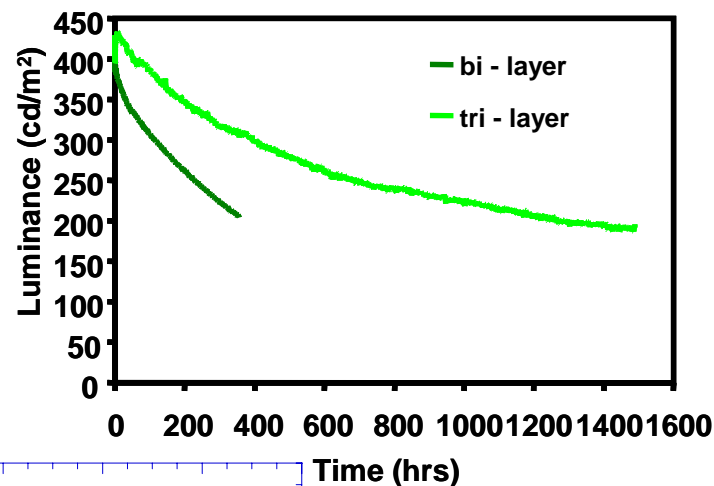


# Lifetime Increases with interlayer C|D|T

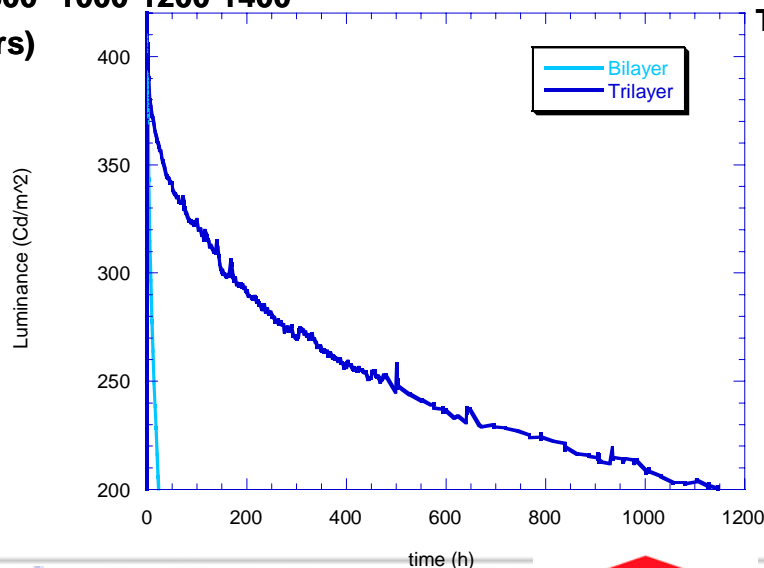
**SCR2** Luminance Decay from 400Cd/m<sup>2</sup>, 80C



**Dow Green K2** Luminance decay from 400Cd/m<sup>2</sup>, 80C



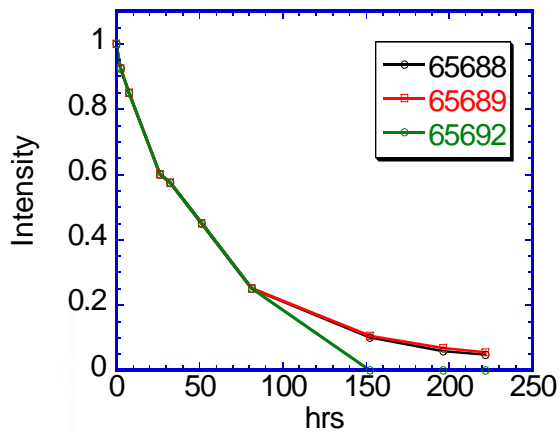
**Blue** Luminance Decay from 400Cd/m<sup>2</sup>, RT



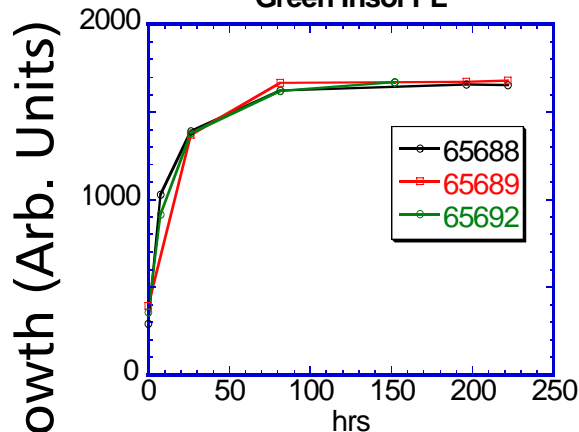
# Insoluble layer – Kinetics

C|D|T

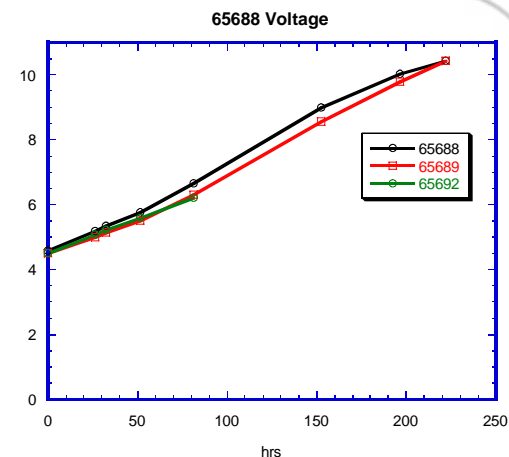
Green from 4000Cd/m<sup>2</sup>



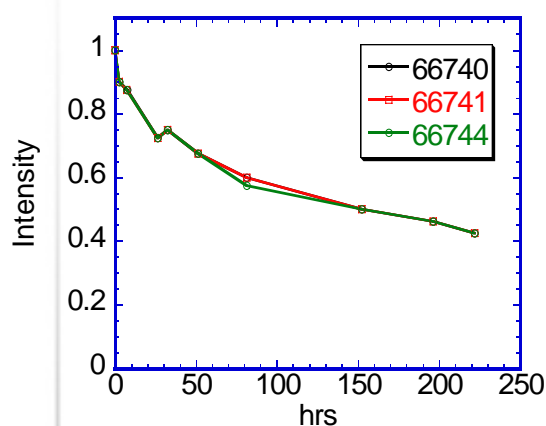
Green Insol PL



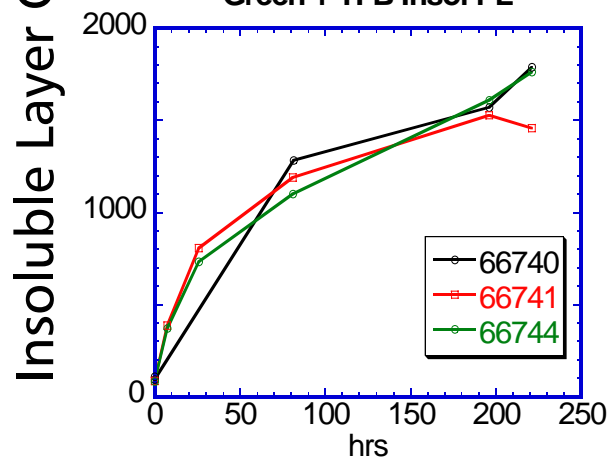
Drive Voltage



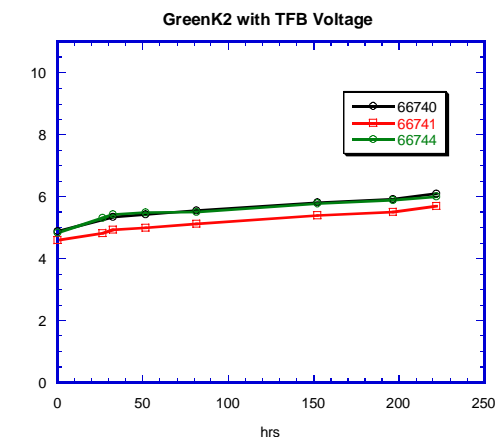
Green + TFB from 4000Cd/m<sup>2</sup>



Green + TFB Insol PL



Drive Voltage



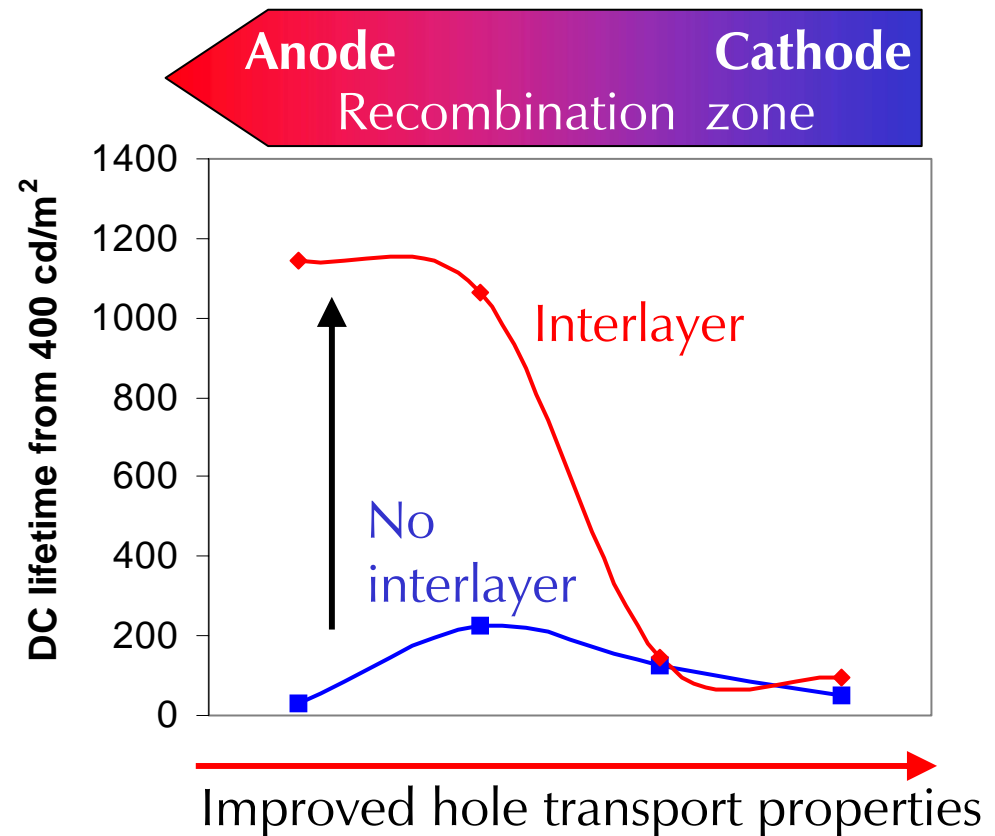
Interlayer Improves efficiency, lifetime, dV/dt and delays insol layer formation



# Evidence for proposed mechanism

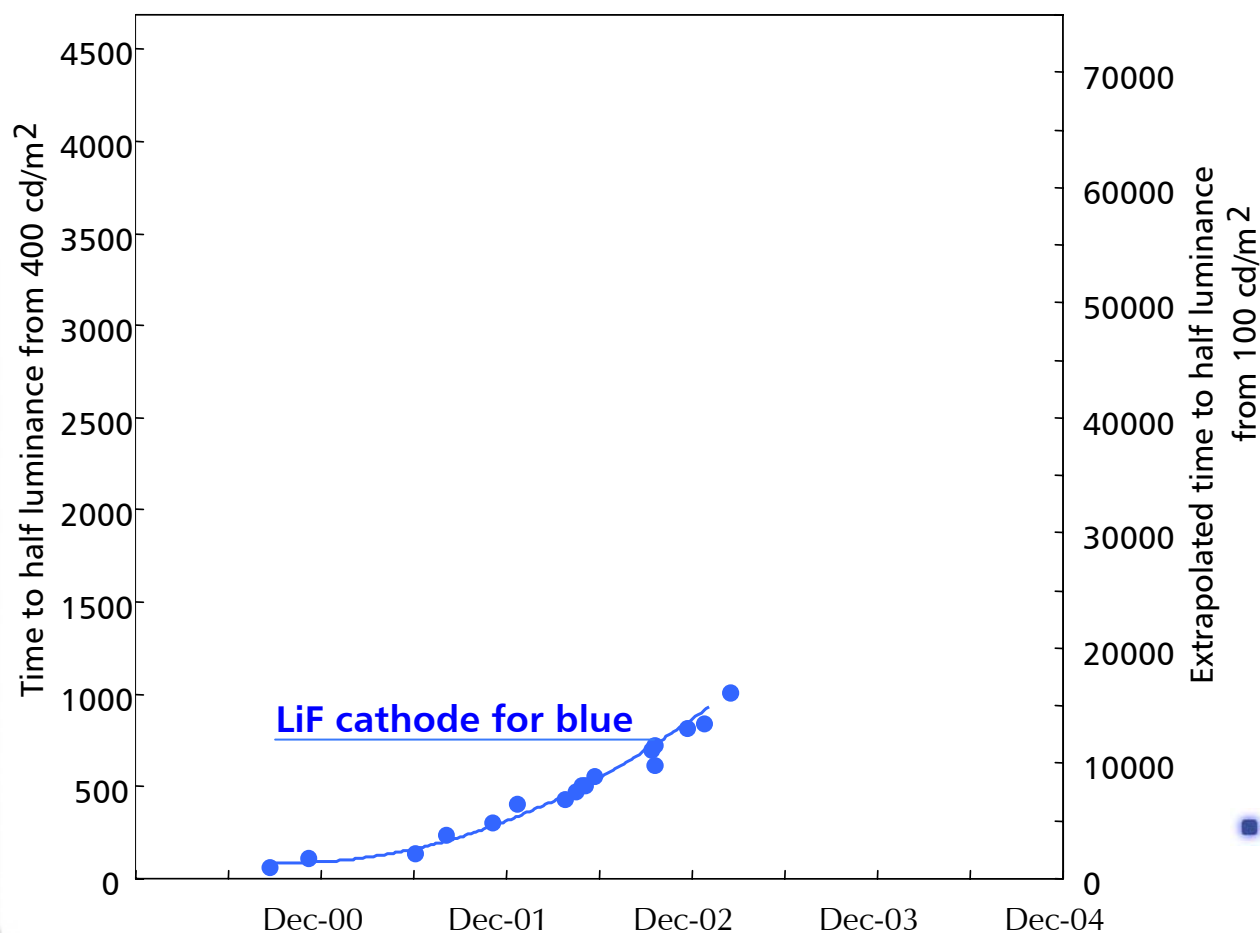
C|D|T

- Devices fabricated with emissive polymers with different hole transport properties
- Recombination zone moves towards anode as hole transporting properties are reduced
- Interlayer has biggest impact on lifetime when recombination zone is near anode
- Confirms possibility of exciton quenching and electron damage at the PEDOT interface



# Blue Lifetime Progress

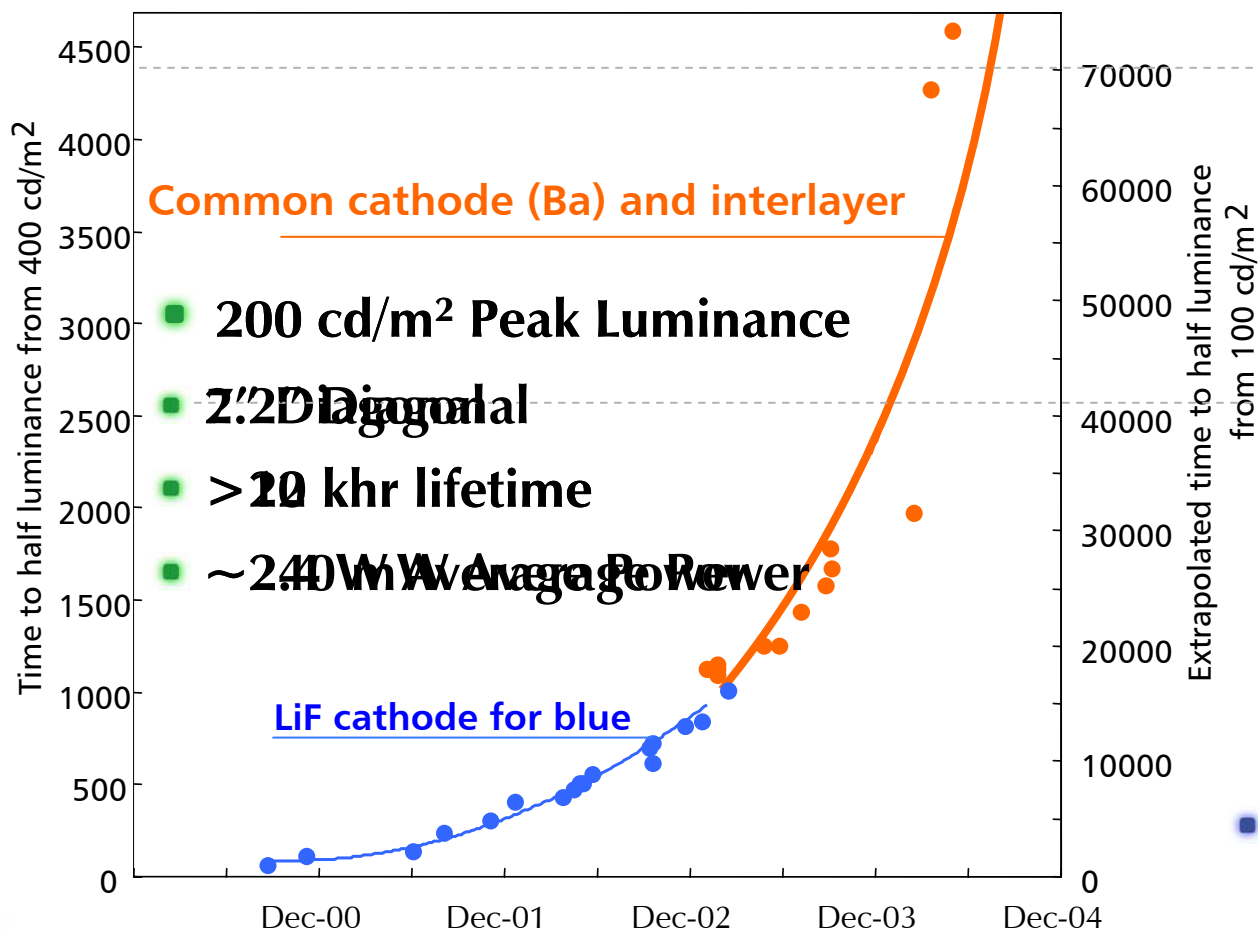
C|D|T



■ *Mobile applications  
now feasible*

# Blue Lifetime Progress

C|D|T



■ *Mobile applications  
now feasible*

# RGB Performance – DC Lifetime

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			At 100 cd/m <sup>2</sup>			Measured Lifetime (hrs at RT)	Extrapolated Lifetime at 100 cd/m <sup>2</sup> , RT	Cathode	Interlayer	dV to half life (V)
	CIE-x	CIE-y	V	cd/ A	Lm /W					
Red	0.68	0.32	3.6	1.7	1.5	1790 hrs at 2000 cd/m <sup>2</sup>	>210,000	Ba	Y	1.6
Green	0.43	0.55	3.4	7.7	7.0	2912 hrs at 2000 cd/m <sup>2</sup>	>190,000	Ba	Y	1.1
Blue	0.16	0.22	5.5	6.9	3.9	>1147 hrs at 800 cd/m <sup>2</sup>	>75,000	Ba	Y	1.0
Yellow	0.50	0.49	4.5	2.1	1.5	2420 hrs at 4000 cd/m <sup>2</sup>	>250,000	Ba	N	2.4
Orange	0.58	0.42	3.4	0.9	0.8	8138 hrs at 1000 cd/m <sup>2</sup>	>300,000	Ba	N	3.8

# RGB Performance – DC Lifetime

C|D|T

			At 100 cd/m <sup>2</sup>			Measured Lifetime (hrs at RT)	Luminance for 10,000hrs Lifetime (DC)	Cathode	Interlayer	dV to half life (V)
	CIE-x	CIE-y	V	cd/ A	Lm/ W					
Red	0.68	0.32	3.6	1.7	1.5	1790 hrs at 2000 cd/m <sup>2</sup>	~700 cd/m <sup>2</sup>	Ba	Y	1.6
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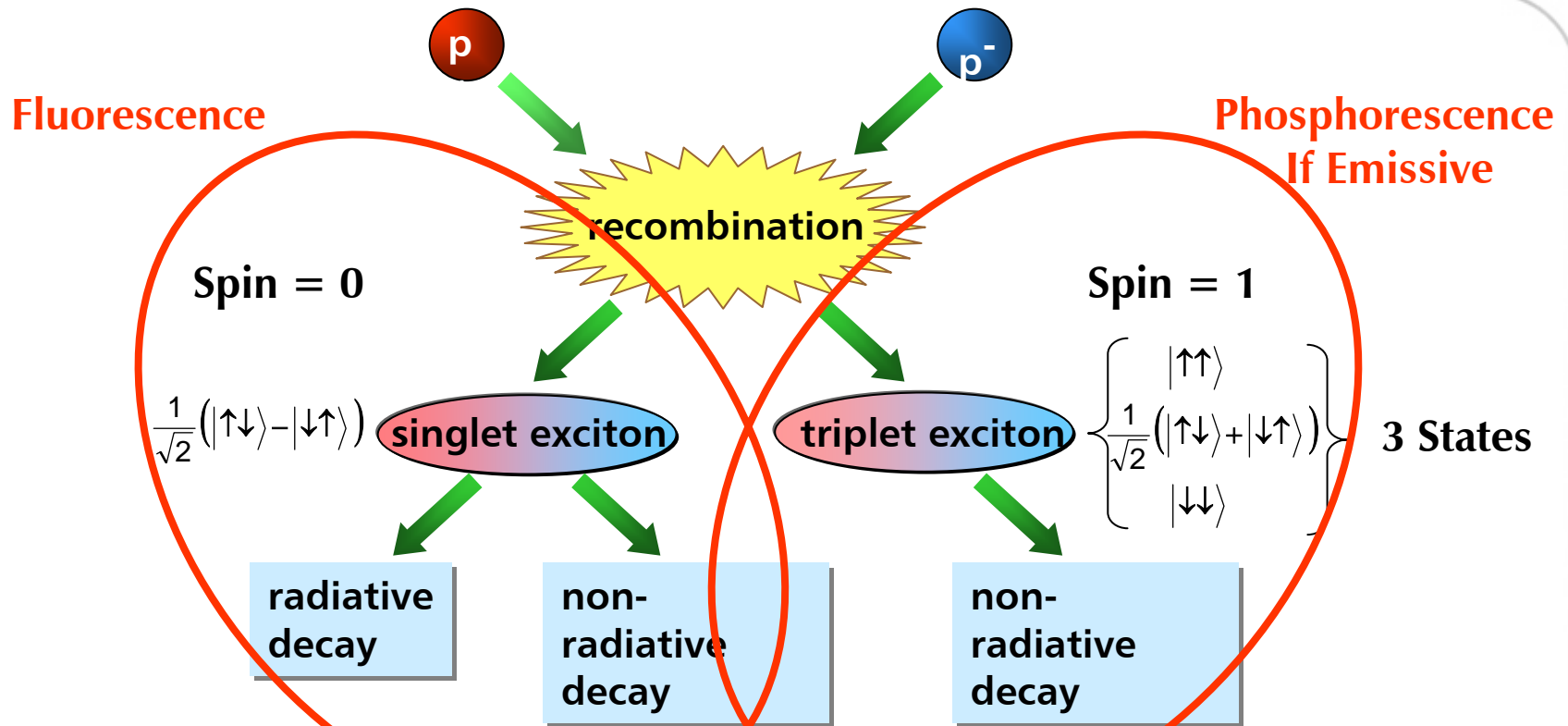
Tri Layer PLEDs

Singlet:Triplet Ratio

Conclusions

# Excited states in polymer LEDs

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Measure generation and decay of singlets, triplets and charges to determine singlet:triplet ratio

IF formation probability of singlet and triplet states is identical then expect singlet:triplet ratio to be **1:3**

# Calculation of the singlet-triplet ratio in OC1C10 LEDs

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Measure triplet induced absorption

Measure EL output

- Several LEPS measured
- All have high singlet ratios
- Small molecules have only 25% singlets as expected

Much Higher  
Than Expected

Triplet generation rate

Singlet generation rate

Singlet formation probability

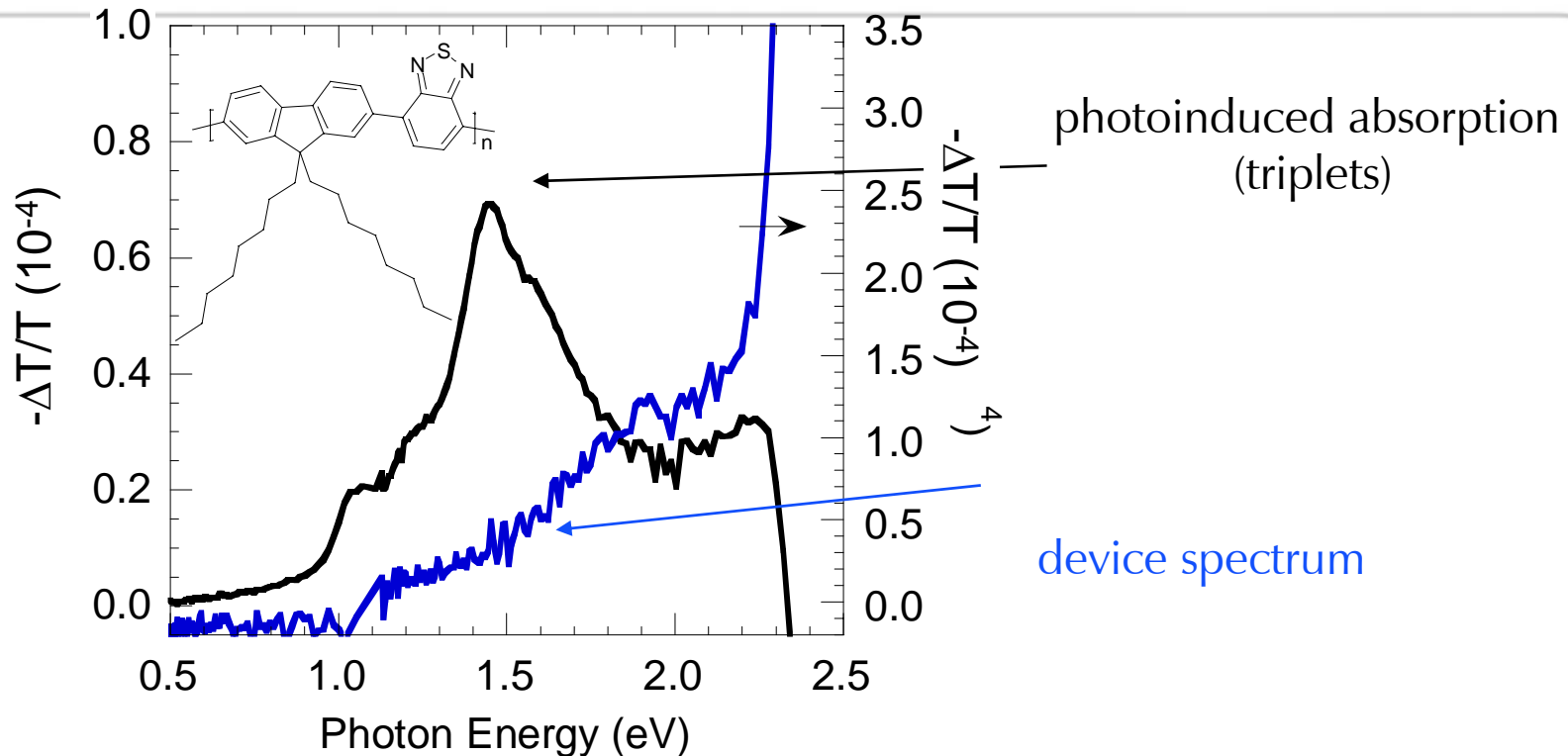
$$r_{st} = \frac{g_s}{g_s + g_t} = 0.83 \pm 0.07$$

Note: Work carried  
at the  
Cavendish Laboratory



# Polyfluorene devices - F8BT

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- No obvious triplet signal in device
- If we assume lifetime = 0.57 ms (as in PIA), and  $s_t > 2 \times 10^{-16} \text{ cm}^2$ 
  - < 6% of excitons formed as triplets! Even less if  $s_t$  larger.
- lifetime should be confirmed

# Singlet-triplet ratio

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## Direct comparison of monomers and polymers

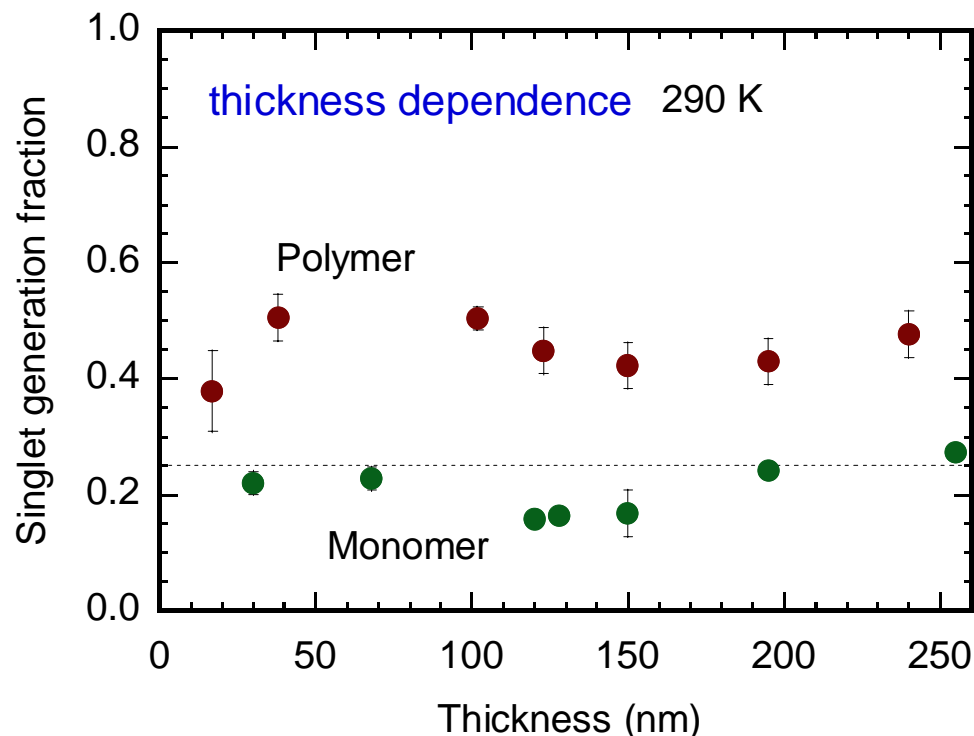
- Recent work from Cavendish published in Nature
- Measurements of monomers and polymers with the same unit cell and identical techniques

- Monomers

 Rst  $\sim 0.25$

- Polymers

 Rst  $\sim 0.5$



Jo Wilson, Anna Köhler, Nature 413, 828 (2001)

# Why are polymers different from small molecules?

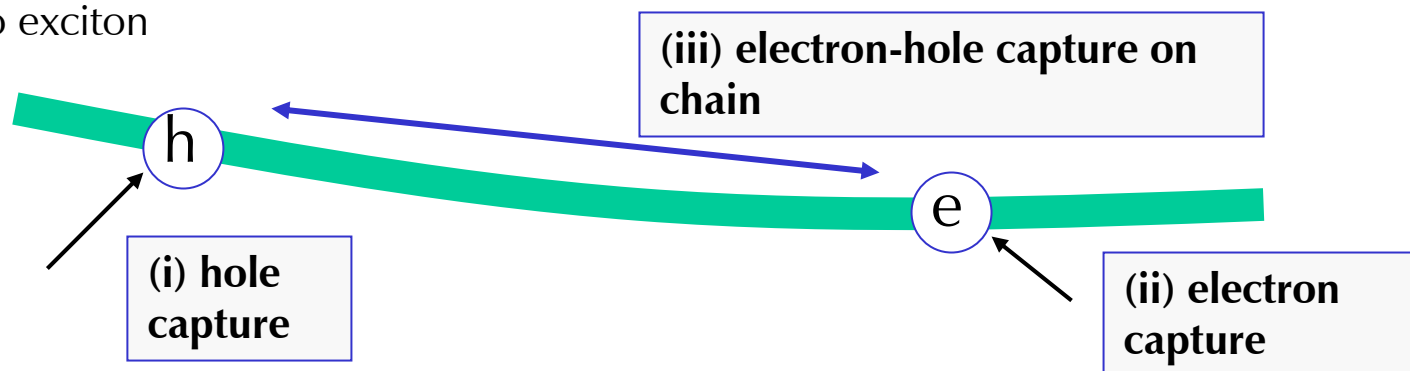
C|D|T

**Small Molecules:** electron-hole capture at separation  $\gg 10$  nm

(Langevin recombination: Coulomb energy  $\gg$  thermal energy)

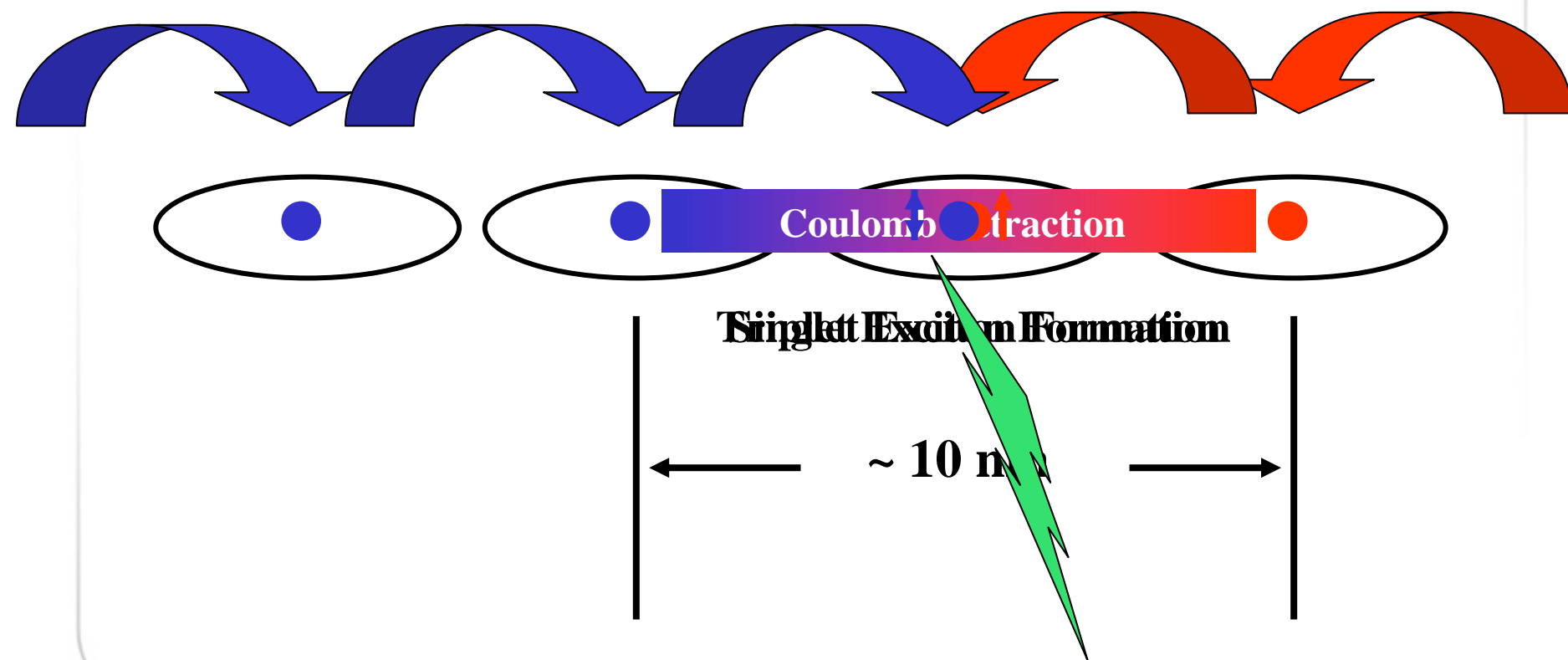
weak inter-molecular e-h delocalisation, so only Coulomb interaction involved in e-h capture cross-section

**Polymers:** electron and hole arrival on polymer chain, and subsequent recombination to exciton



step (iii) spin-dependent?

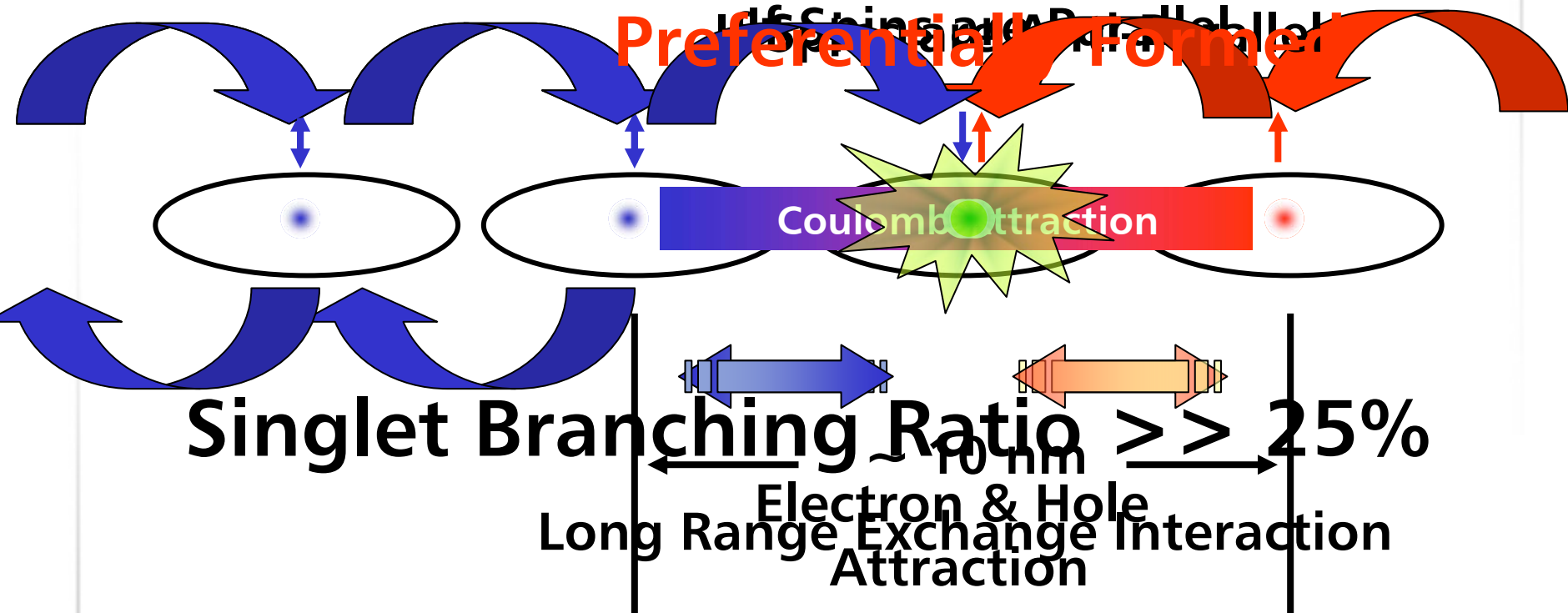
- delocalisation of electron and hole wavefunctions along chain allows **exchange interaction** at long range for charges on same chain this favours singlet bound state at e-h capture (typical range 10 nm)  
(Beljonne et al J. Chem. Phys. **102**, 2042, 1995)



Couple Monomers Conjugatively

Excitons with  $S=0$

Preferentially Formed



To Make a Light Emitting Polymer

# Why is the LEP device Efficiency not Higher ?

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Because there are other loss mechanisms in the device

- Electrons or Holes passing through the device
- Exciton quenching at
  - PEDT/LEP Interface
    - i.e. Exciton Quenching occurs at PEDT/LEP Interface
  - Cathode

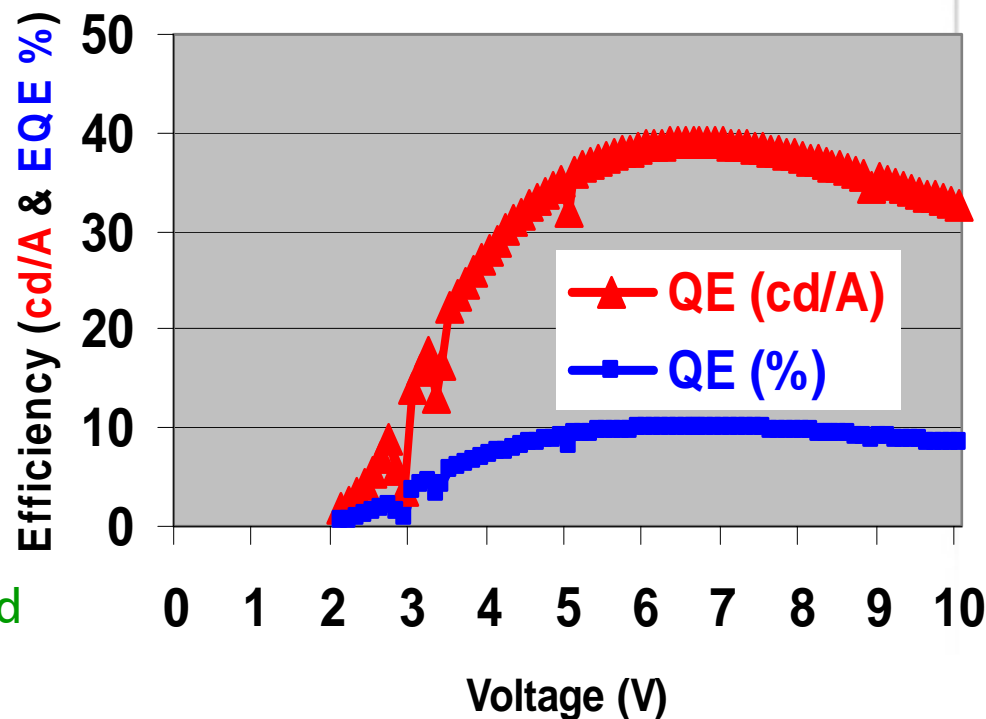
# Ad-Vision Results on Thick Green/Yellow LEP

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- Device Structure: ITO/PEDT:PSS (20-30 nm)/LEP (250 nm)/Ca/Al

- Recombination removed from quenching sites such as the cathode and PEDT:PSS

- EQE > 10 %
- IQE > 33 %
- PL Efficiency 61 %
- Singlet Ratio ~ 50+ %

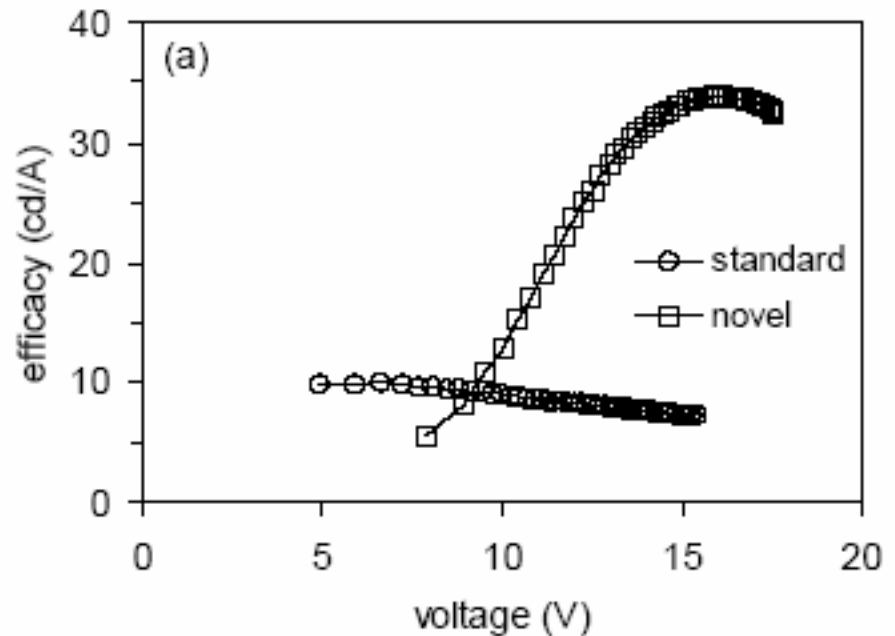


- Note 33 Cd/A (8% EQE) reported by TDK, Yamagata University, UCLA

- This supports the work at the University of Cambridge and suggests significant efficiency gains are still possible with optimised device design

*Data supplied by Dr Melissa Kreger & Professor Sue Carter*

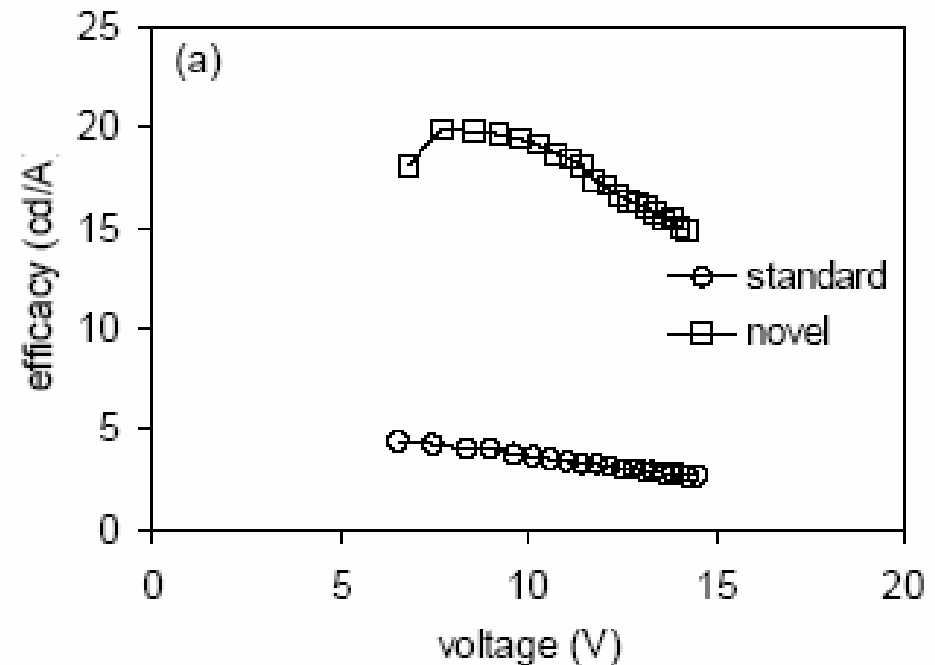
- **Device Structure: ITO/New HTL/Covion Super Yellow/Ba/Al**
- **Recombination removed from quenching sites such as the cathode and PEDT:PSS**
- **EQE > 12 %**
- **IQE > 35 %**
  - **Assuming only observe 34% of generated light**
- **PL Efficiency 41 %**
- **Singlet Ratio close to 100 %**



*E A Meulenkaamp et al  
Philips, Eindhoven, 2004*



- Device Structure: ITO/New HTL/Covion Spiro PF/Ba/Al
- Recombination removed from quenching sites such as the cathode and PEDT:PSS
- EQE > 12.5 %
- IQE > 36 %
  - Assuming only observe 34% of generated light
- PL Efficiency 38 %
- Singlet Ratio close to 100 %

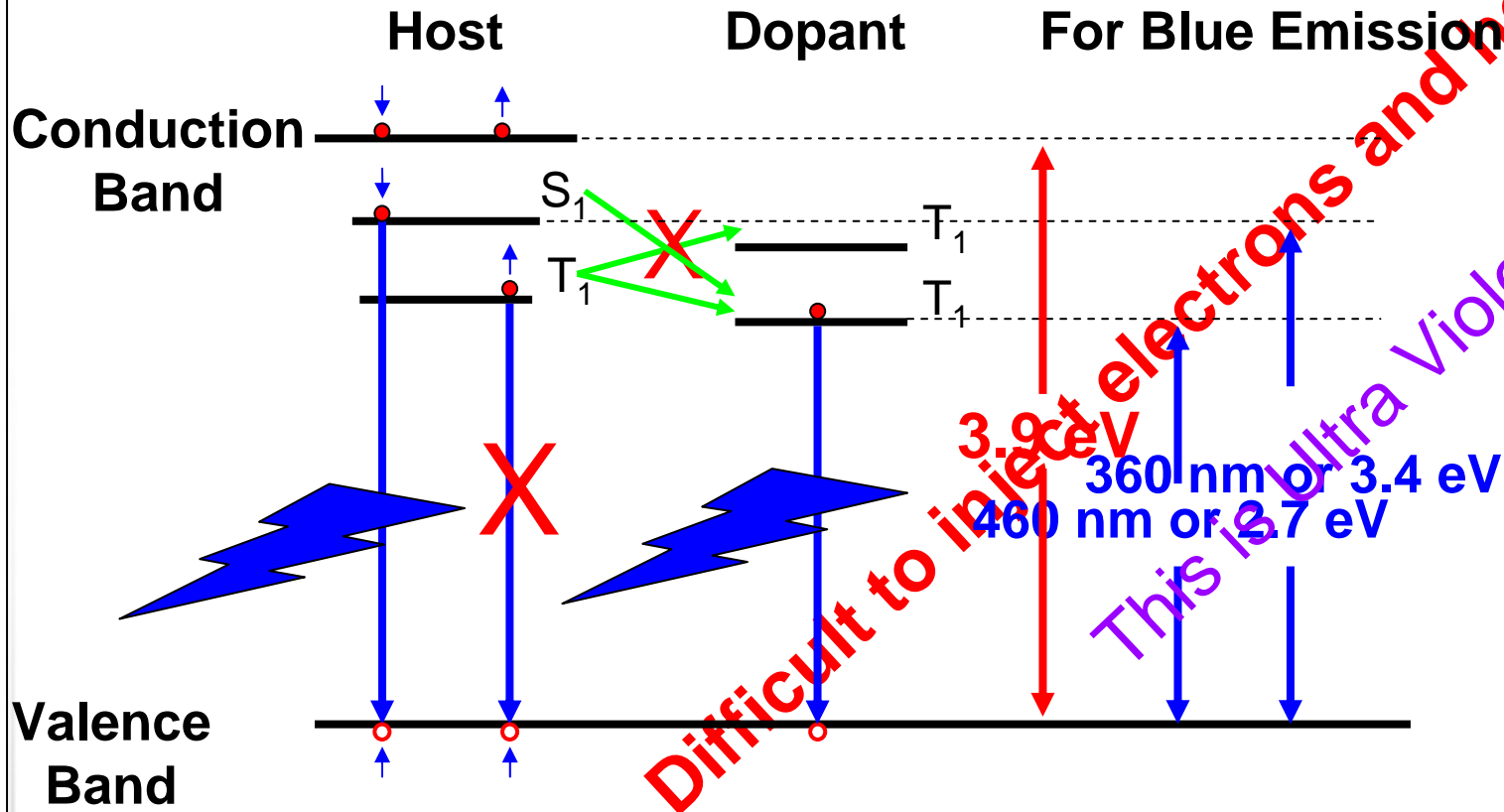


*E A Meulenkaamp et al  
Philips, Eindhoven, 2004*

- More singlets than expected in polymer LEDs
- Understanding loss mechanisms results in significant efficiency improvements in LEP diodes
  - >25% singlet generation probability demonstrated in real diodes
  - For blue: Is this the only way to high efficiency?

# Why is Blue Phosphorescent Emission Difficult?

C|D|T



**Issues:**

Need Stable UV Emitter

Very Large Barriers to Electron and Hole Injection

- More singlets than expected in polymer LEDs
- Understanding loss mechanisms results in significant efficiency improvements in LEP diodes
  - >25% singlet generation probability demonstrated in real diodes
  - For blue: Is this the only way to high efficiency?

■ **MAYBE**

Introduction

Understanding PLEDs

Tri Layer PLEDs

Singlet:Triplet Ratio

Conclusions

- Blue lifetime increasing rapidly
  - > 70,000 hours
- Singlet:Triplet Ratio
  - SMF ~ 25%
  - P-OLED >> 25%
- PLED technology is gathering momentum
- CDT is established as the technology leader in this space



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